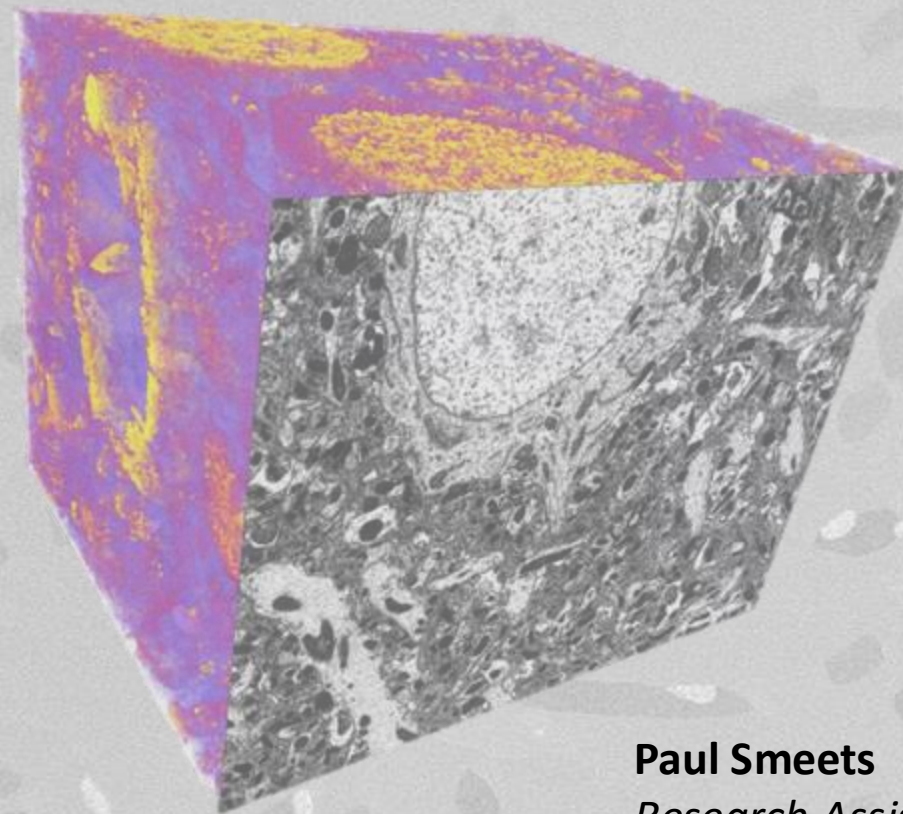


The Power of Plasma:

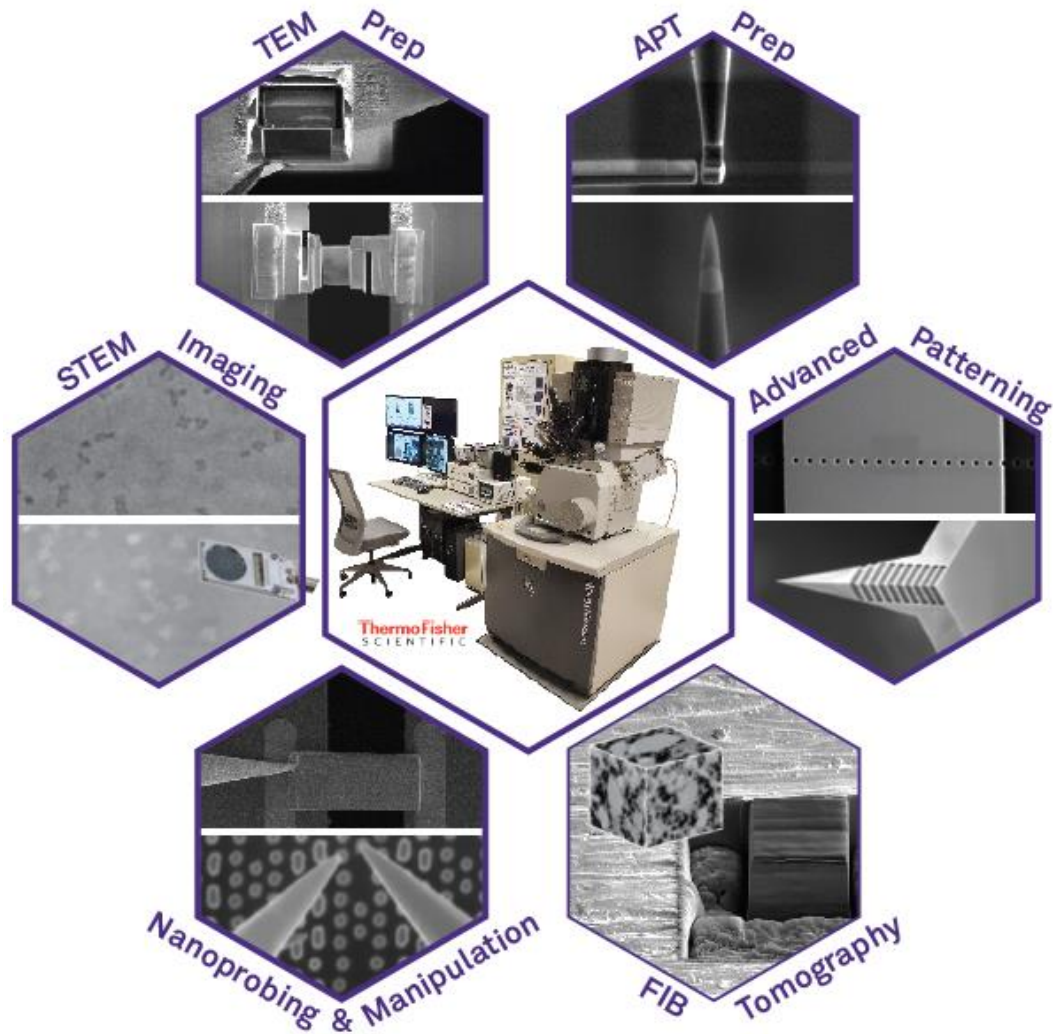
Introducing the Thermo Fisher Hydra Plasma FIB-SEM



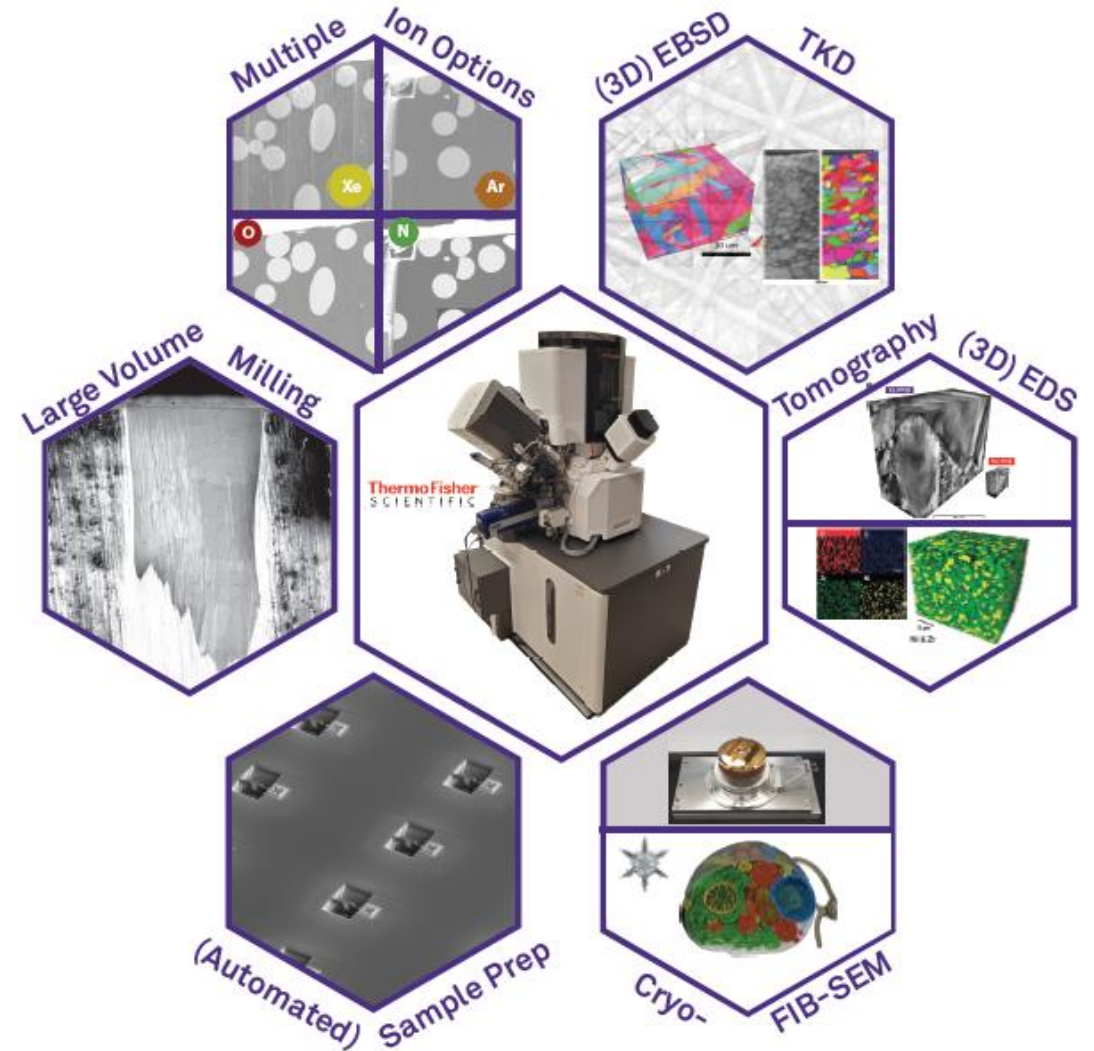
Paul Smeets
*Research Assistant Professor
Materials Science and Engineering
Northwestern University*

EPIC – FIB Instrumentation

FEI Helios Nanolab 600 FIB-SEM



Thermo Fisher Hydra Plasma FIB-SEM



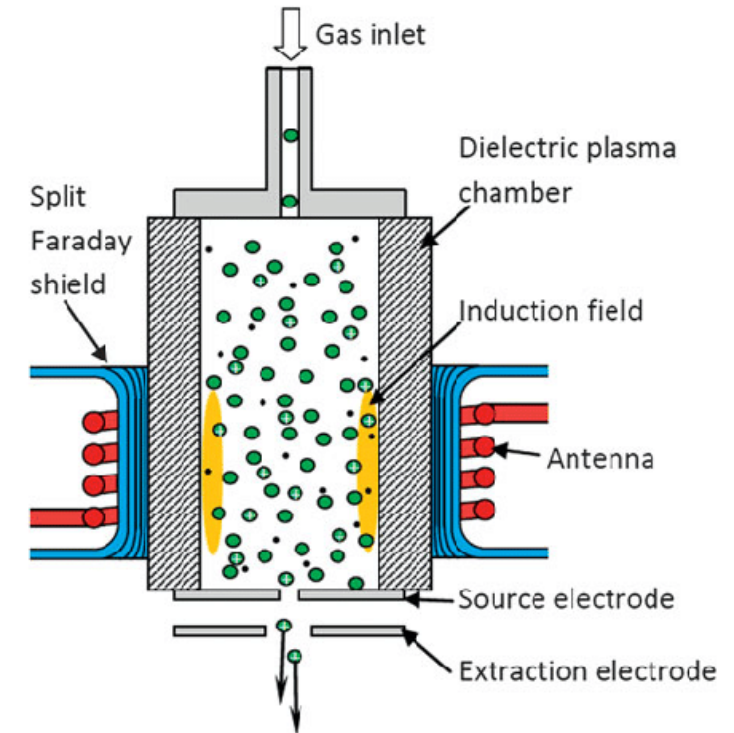
What is a Plasma?

- 'Fourth state of matter'

- Inlet gas gets ionized by induction magnetic field

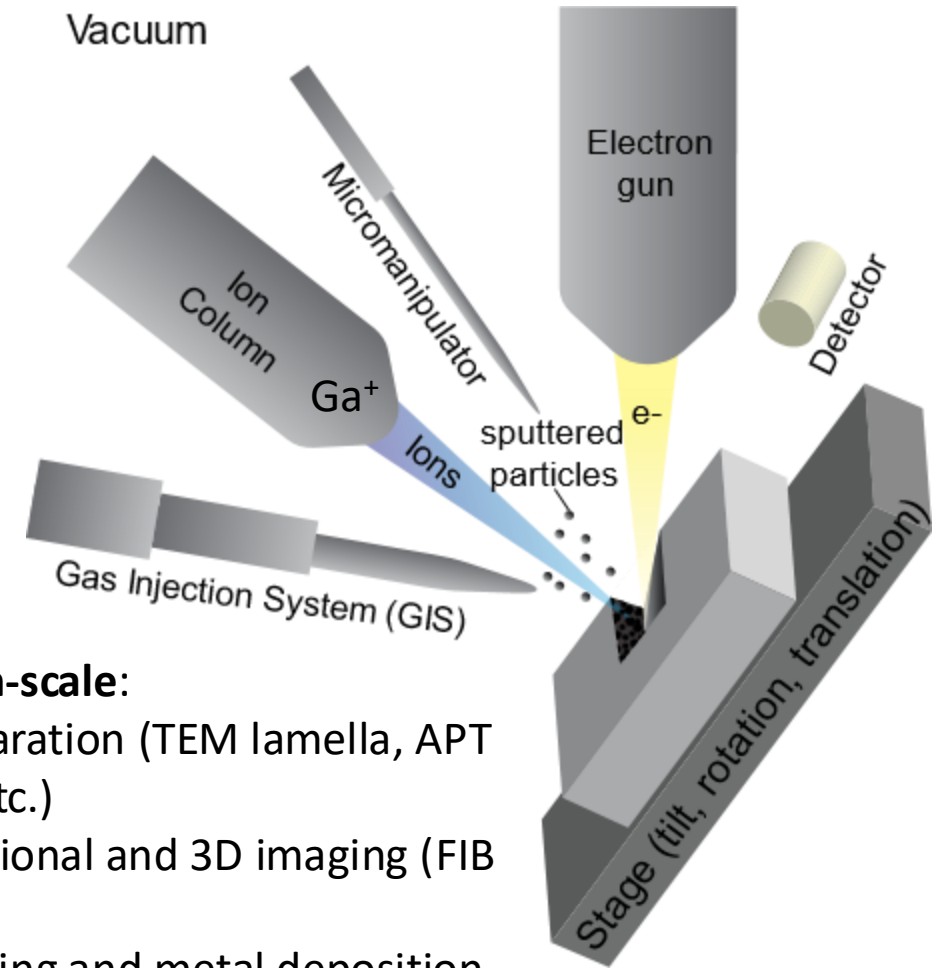
- Extraction of positive ions

$$E = -N(\Delta\phi_B/\Delta t)$$



What is a Focused Ion Beam – Scanning Electron Microscopy (FIB-SEM)?

Tech Talk – Fundamentals of FIB-SEM

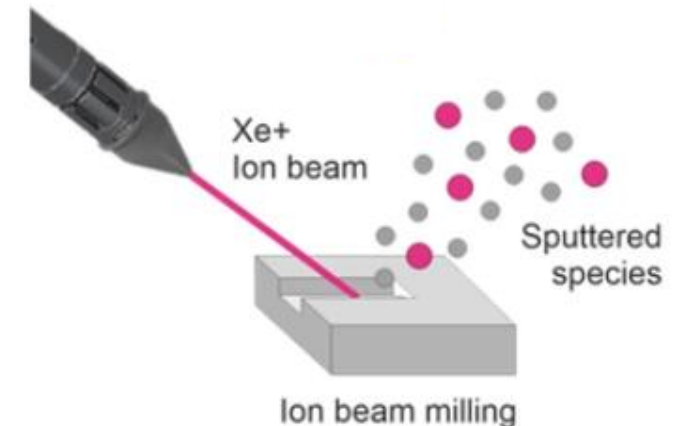
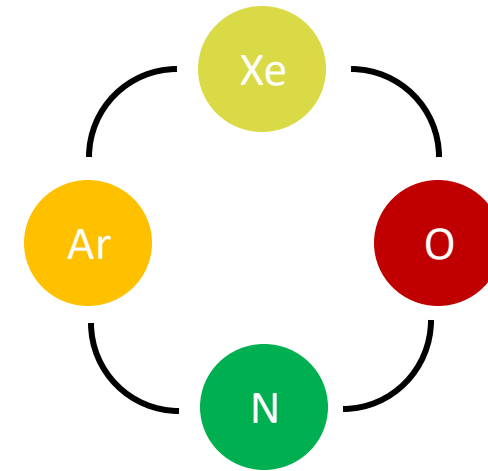


Nano- to micron-scale:

- Sample preparation (TEM lamella, APT tips, X-ray , etc.)
- 2D cross-sectional and 3D imaging (FIB tomography)
- Micromachining and metal deposition via GIS

Benefits of using Plasma in a FIB-SEM

- Four different ion species
 - Each deliver different outcomes
 - Switching species in < 10 min
- Flexibility in sample preparation / characterization
 - Match the ion to the sample
- High ion beam currents available



High Throughput Xe⁺ Milling – Conventional FIB vs PFIB

Ion Beam Conditions

Ga⁺ 30 kV; 21 nA

Xe⁺ 30 kV; 2.5 μA

Instrument

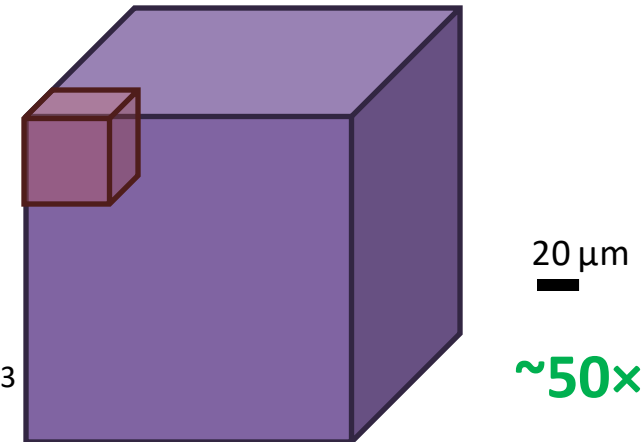
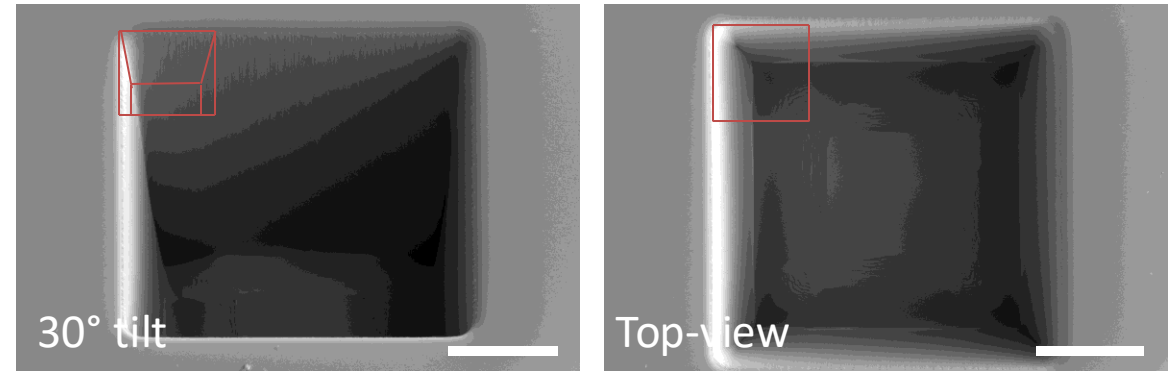
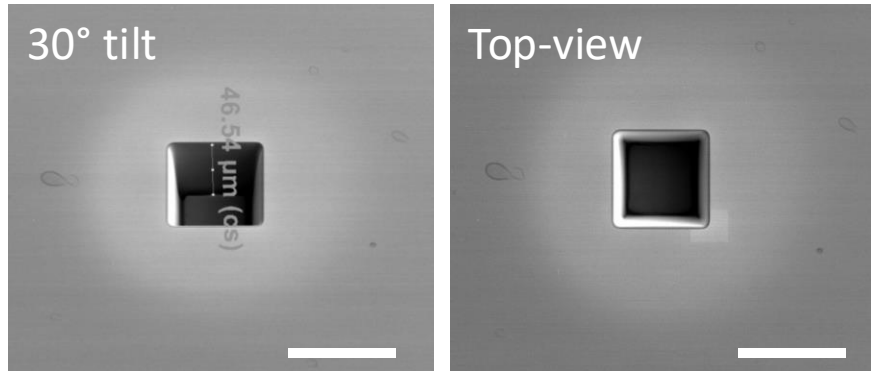
Helios Nanolab 600 FIB-SEM

Hydra PFIB

Milling Time

1 hr

1 hr



Si Volume Milled

$6.4 \times 10^4 \mu\text{m}^3$

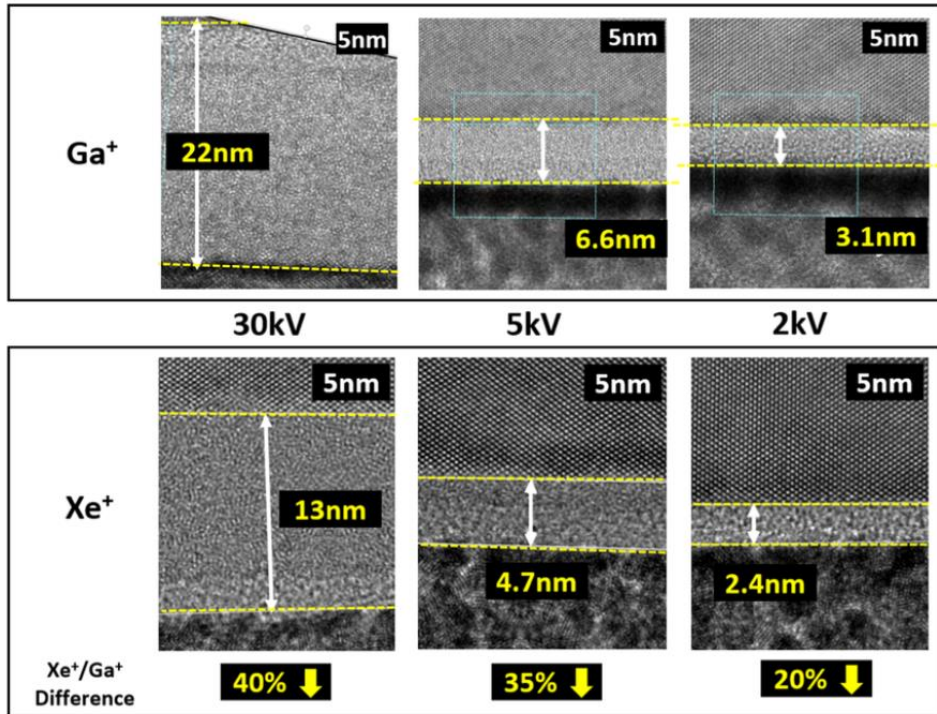
$3.0 \times 10^6 \mu\text{m}^3$

~50x

PFIB Benefits over Conventional Ga⁺ FIB-SEM

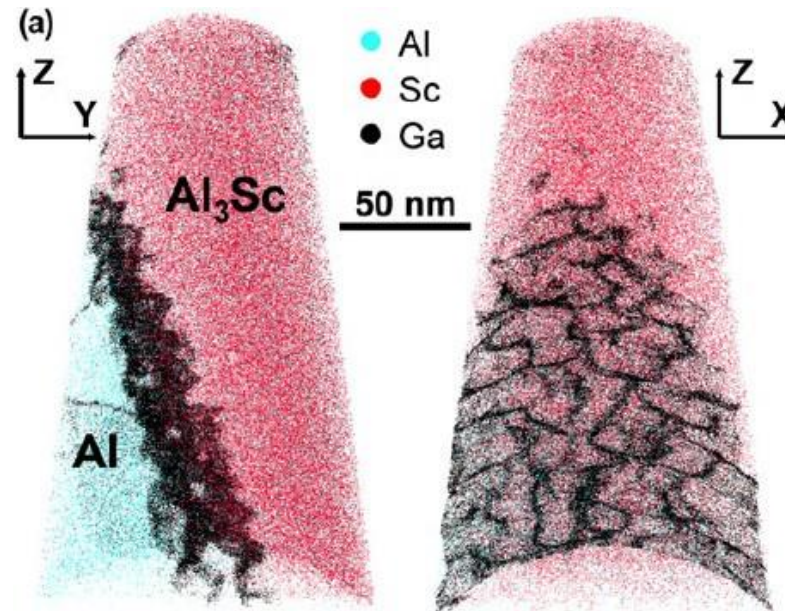
Less surface damage

TEM lamella (Si)



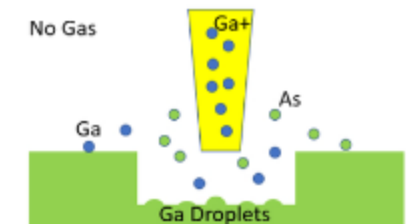
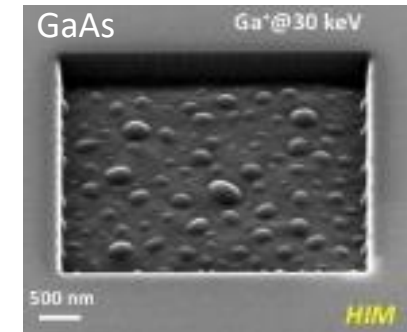
Burnett, T.L. *et al. Ultramicroscopy* **161**, 119 (2016)

Ga⁺ contamination
Al-based alloy using
Atom Probe Tomography



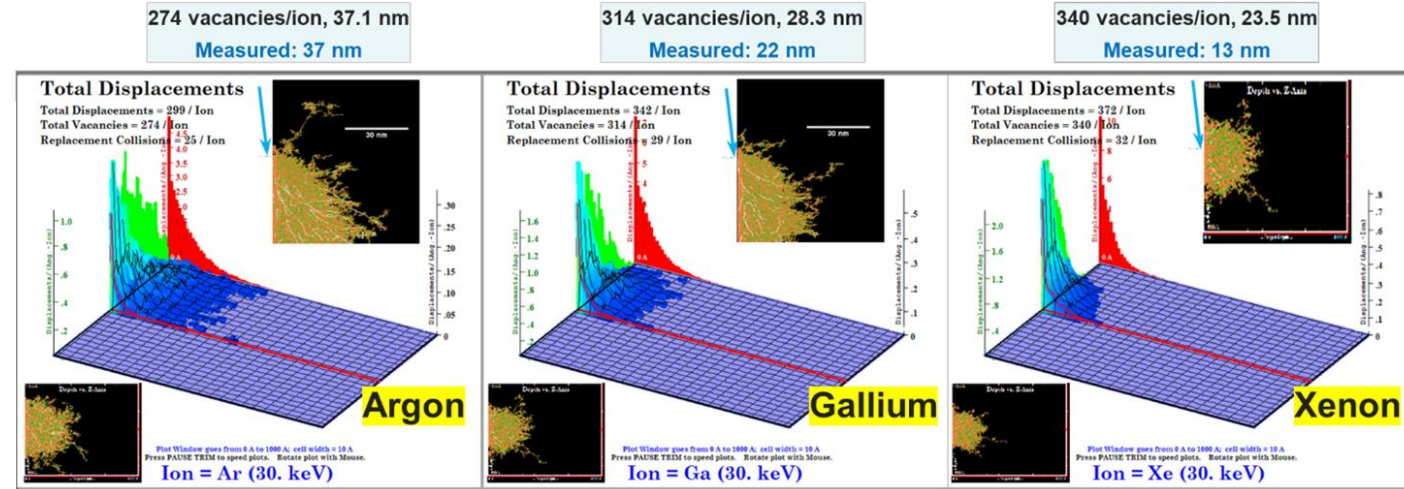
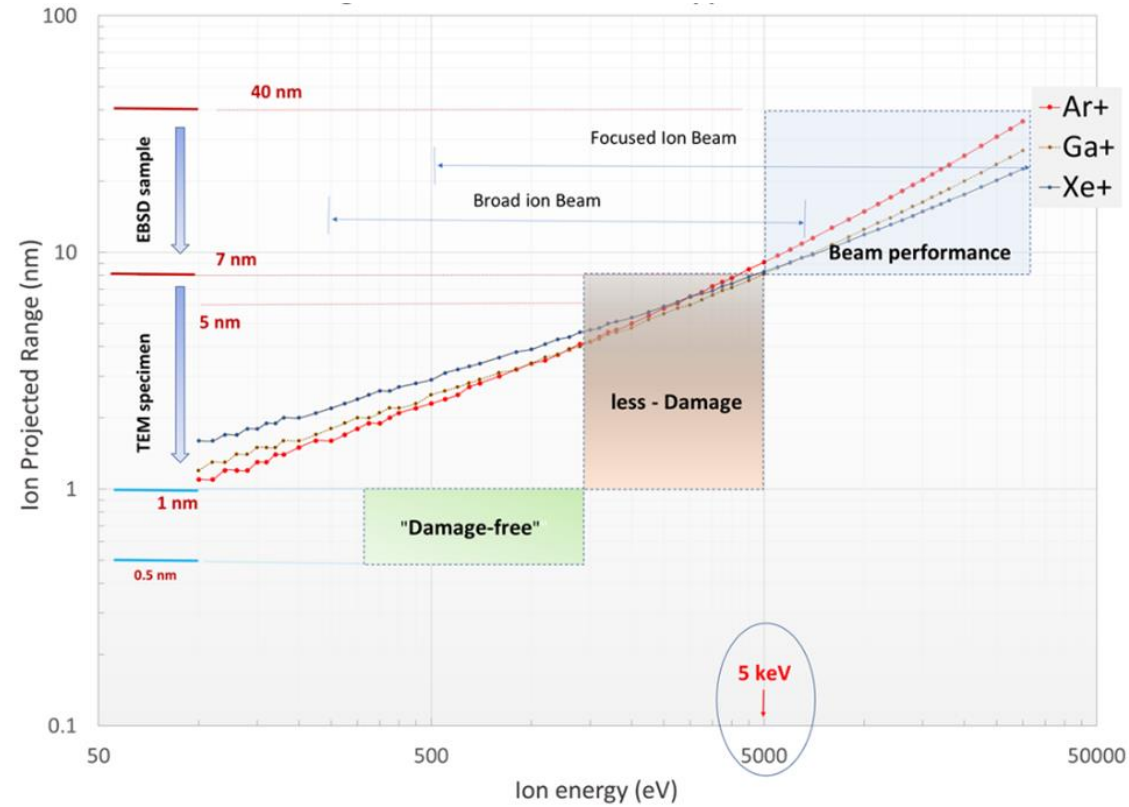
Gault, B. *et al. Journal of Materials Research* **33**, 4018 (2018) Xia, D. *et al. Applied Surface Science* **538**, 147922 (2021)

Milling Ga-based materials



Exploring various Ion Interactions: Ga⁺ vs Xe⁺ vs Ar⁺

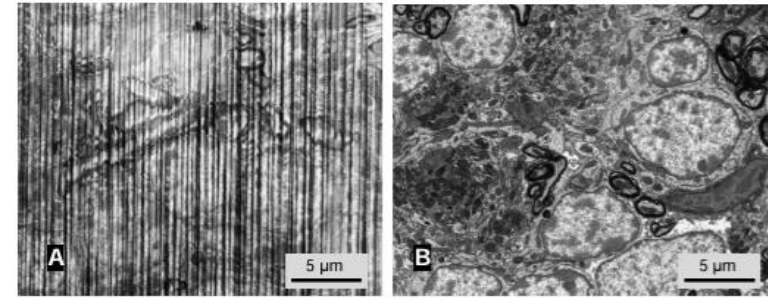
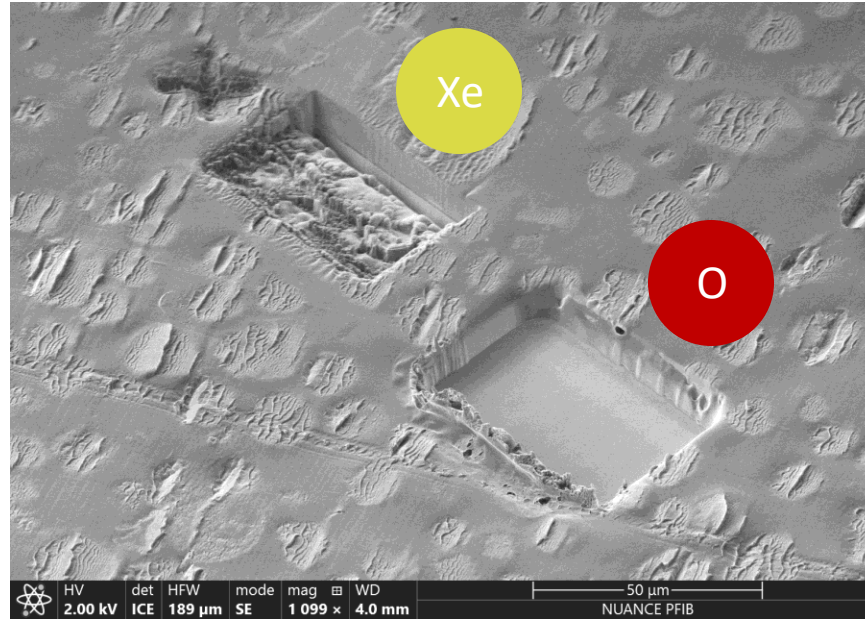
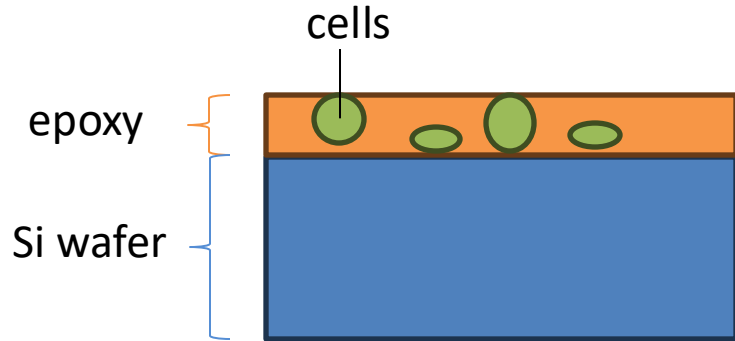
Ion range in Si vs kV



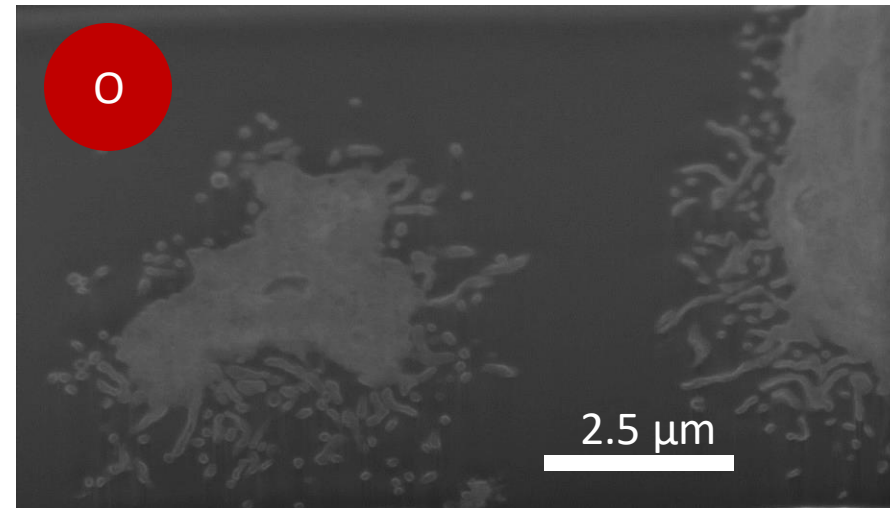
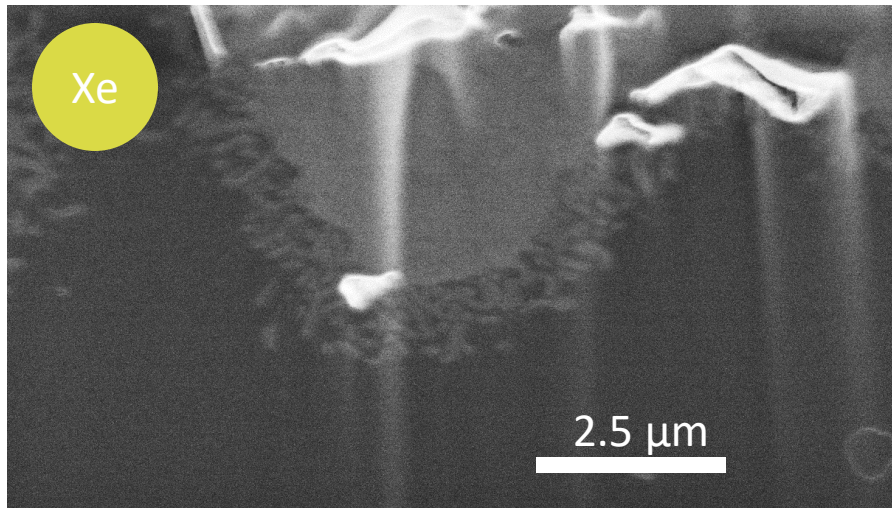
Tradeoff between Ion Range and Damage Intensity (milling rate)

Exploring Ion Interactions: Oxygen vs Xenon

Co-culture of mouse macrophages and cancer tumor cells



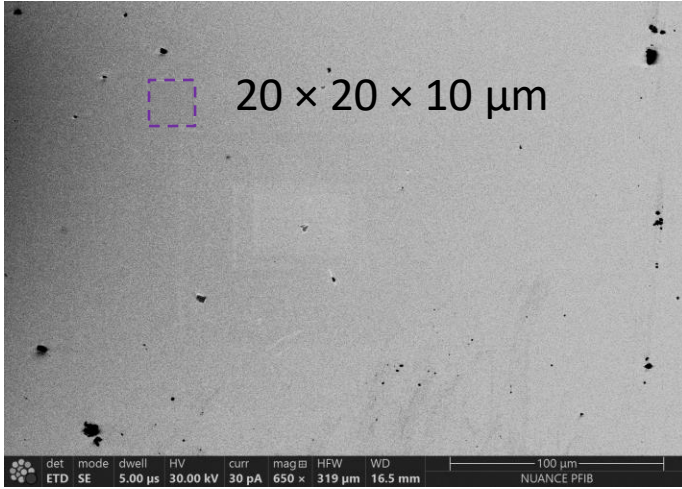
Chemically fixed mouse brain tissue embedded in LR White resin. (A) Gallium FIB milling at 30 kV, 65 nA. (B) Oxygen PFIB milling at 30 kV, 45 nA. Image taken with in-column detector at 2 kV.



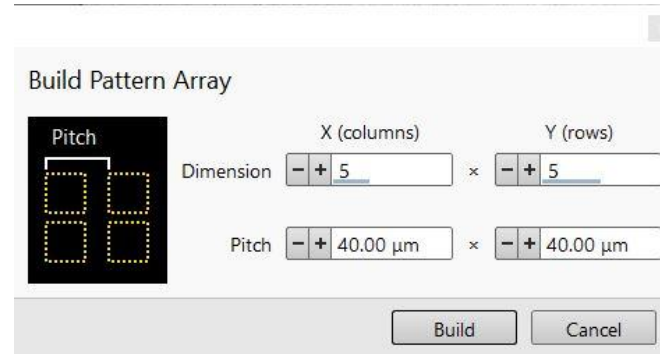
Rapid and Convenient Micromachining

Micromachining pattern array

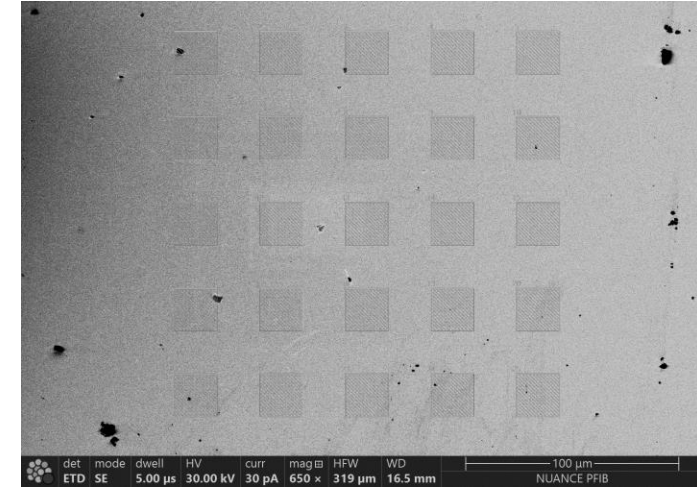
Step 1 → build pattern



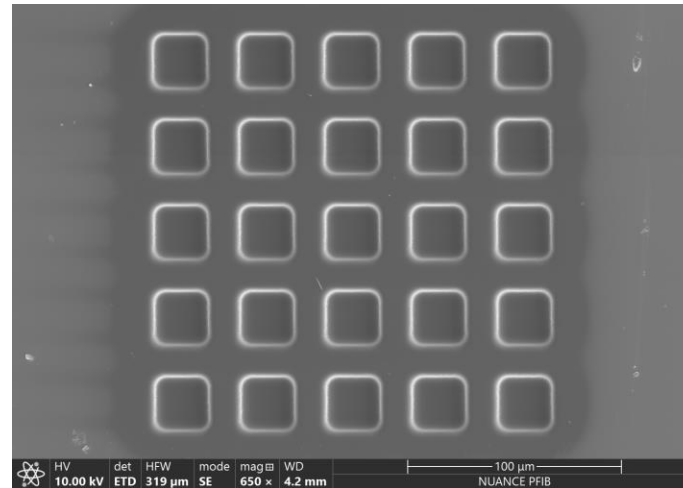
Step 2 → build pattern array



Step 3 → mill pattern array



Step 3 → final imaging result (SEM)



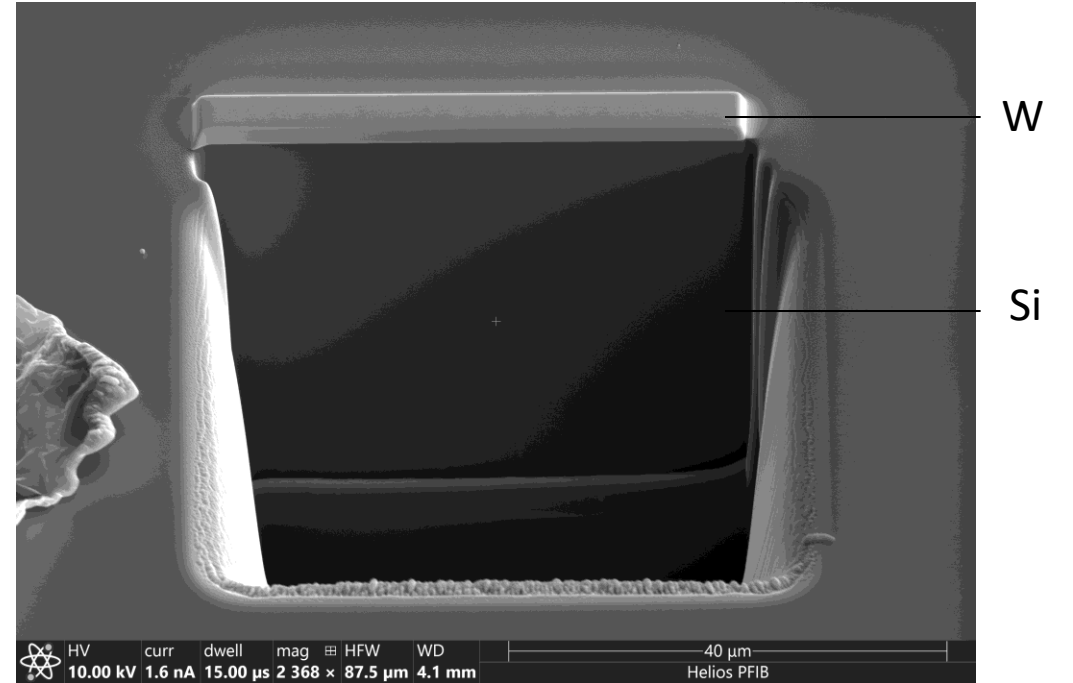
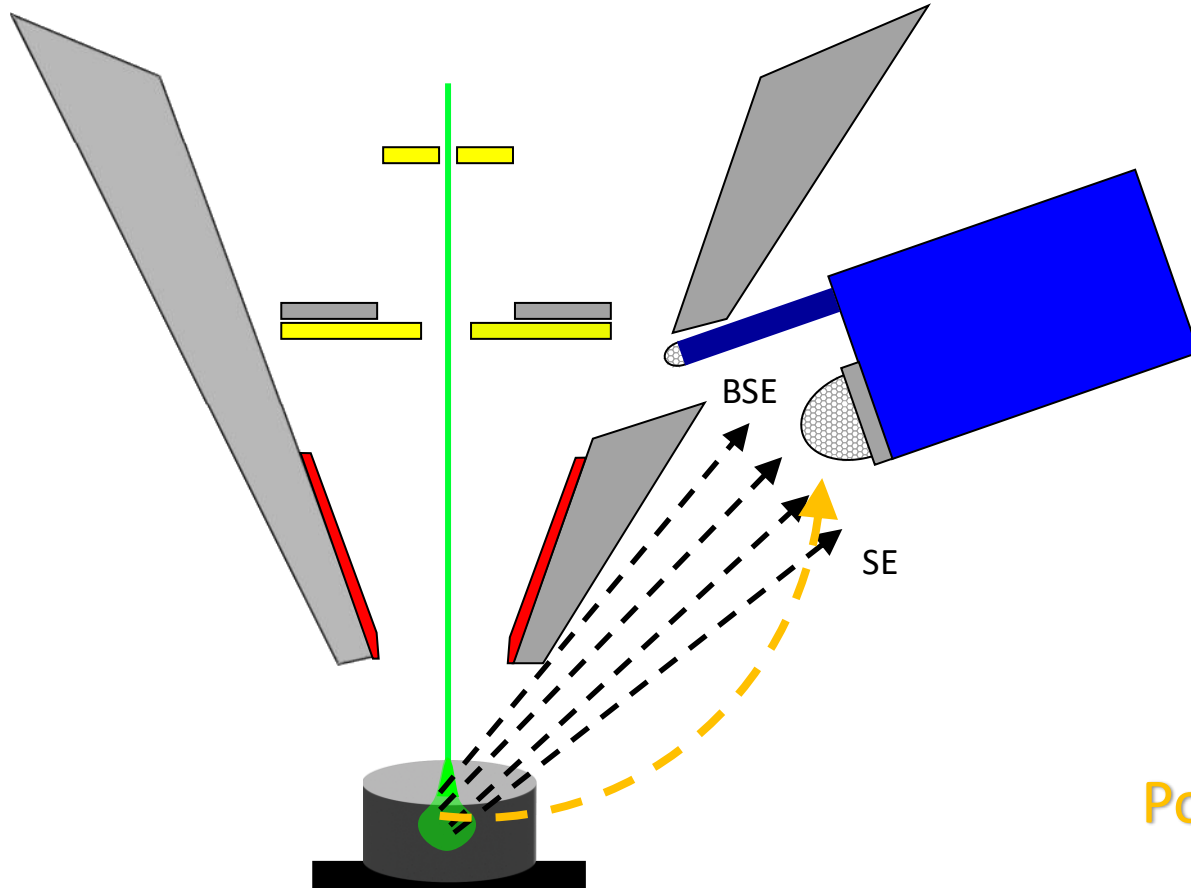
Volume milled: $10^5 \mu\text{m}^3$

Total time: ~5 min

Imaging Detectors

1) Everhart Thornley Detector (ETD)

Secondary Electron (SE) Mode

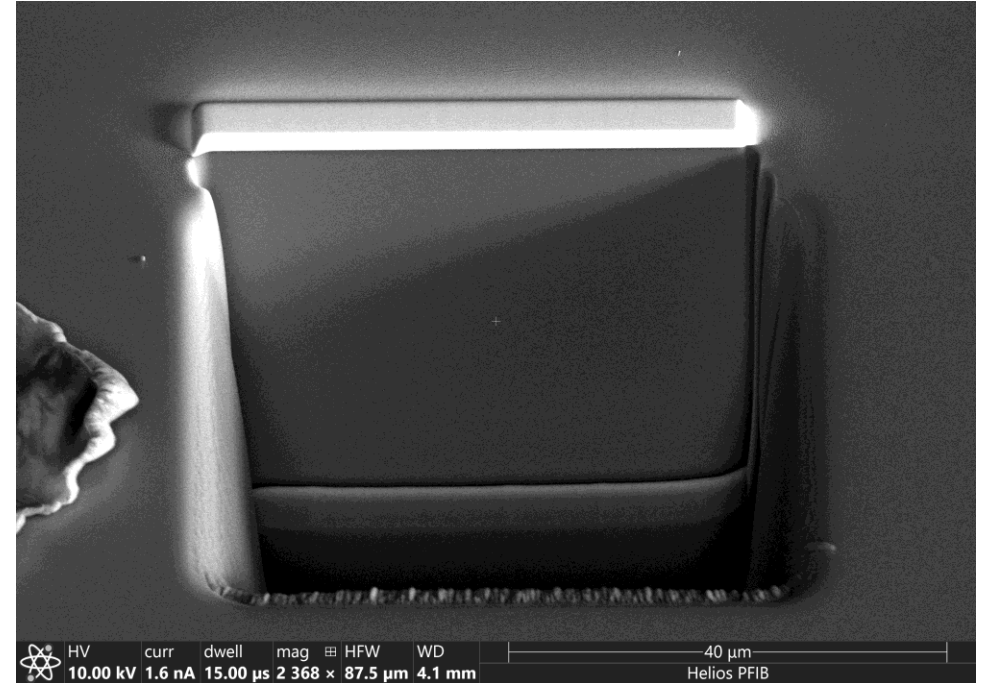
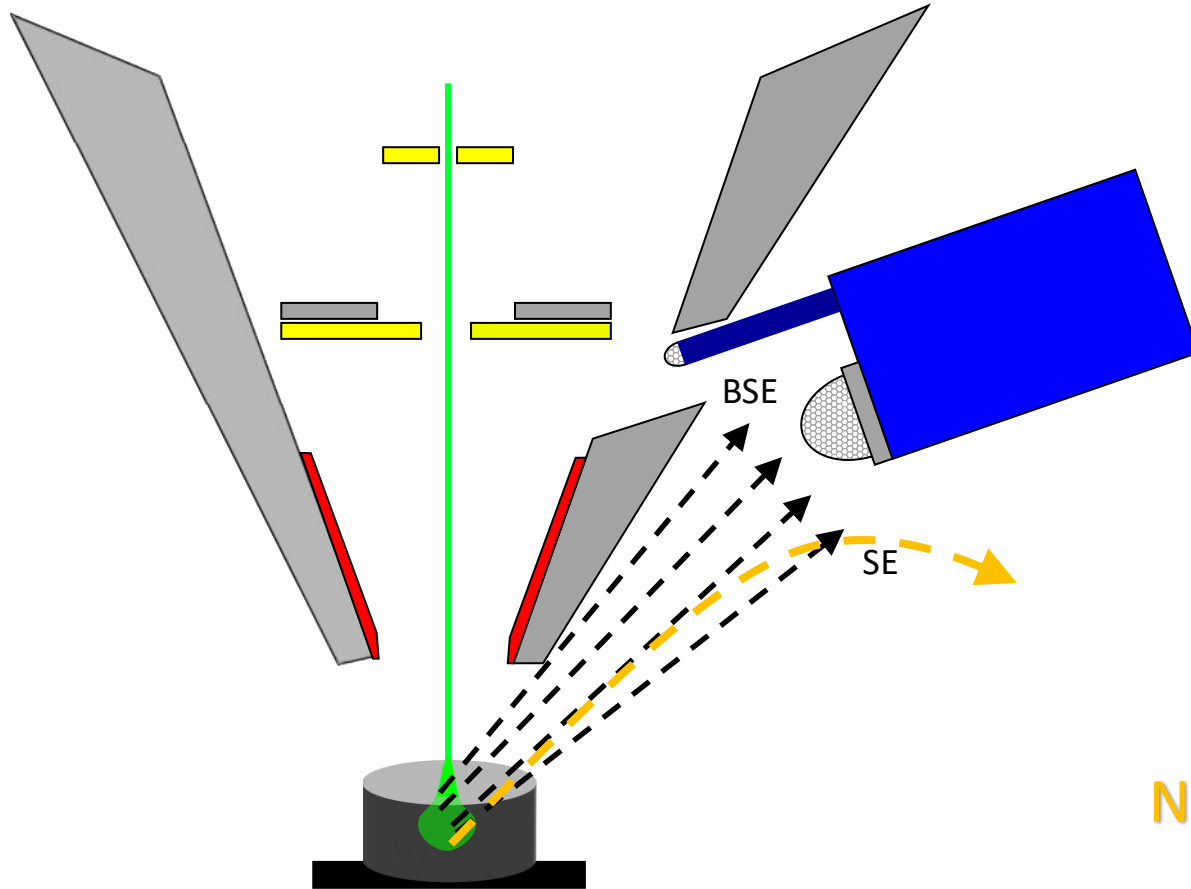


Positive grid bias to attract lower energy SEs

Imaging Detectors

1) Everhart Thornley Detector (ETD)

Backscatter Electron (BSE) Mode

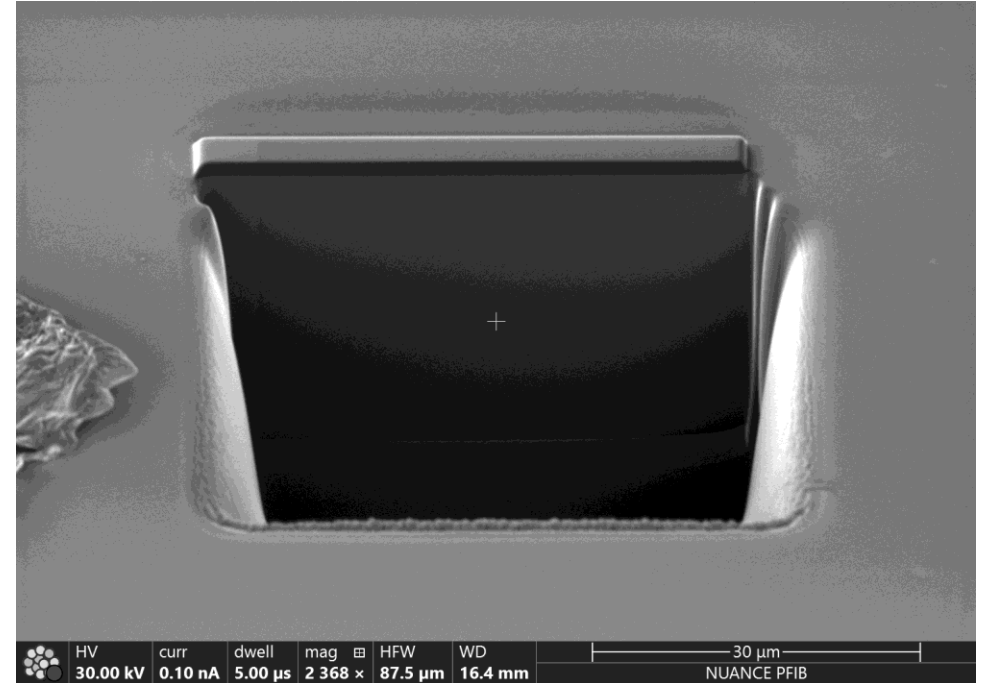
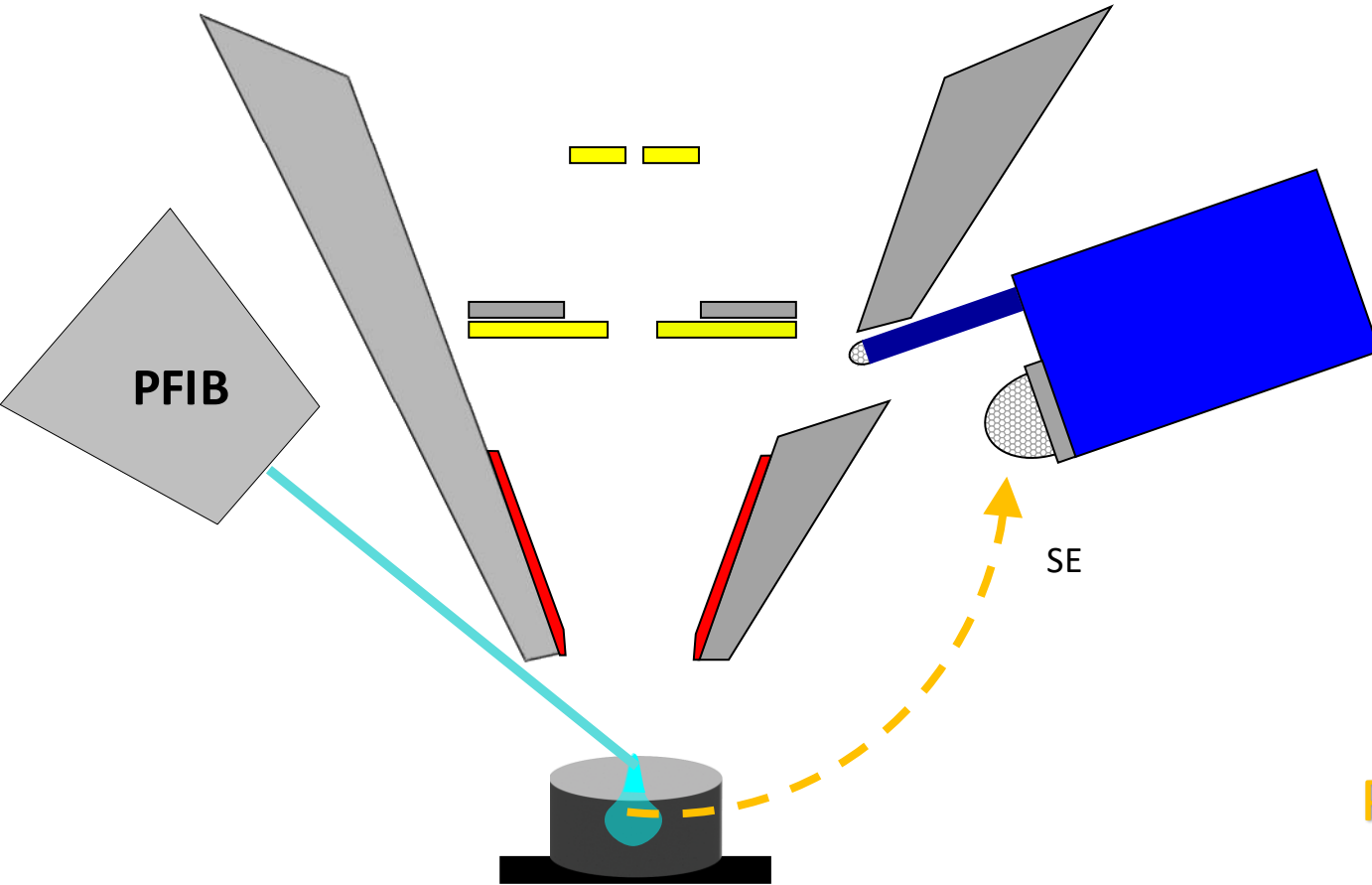


Negative grid bias to repel lower energy SEs

Imaging Detectors

1) Everhart Thornley Detector (ETD)

Ion Beam Induced (SE) Mode

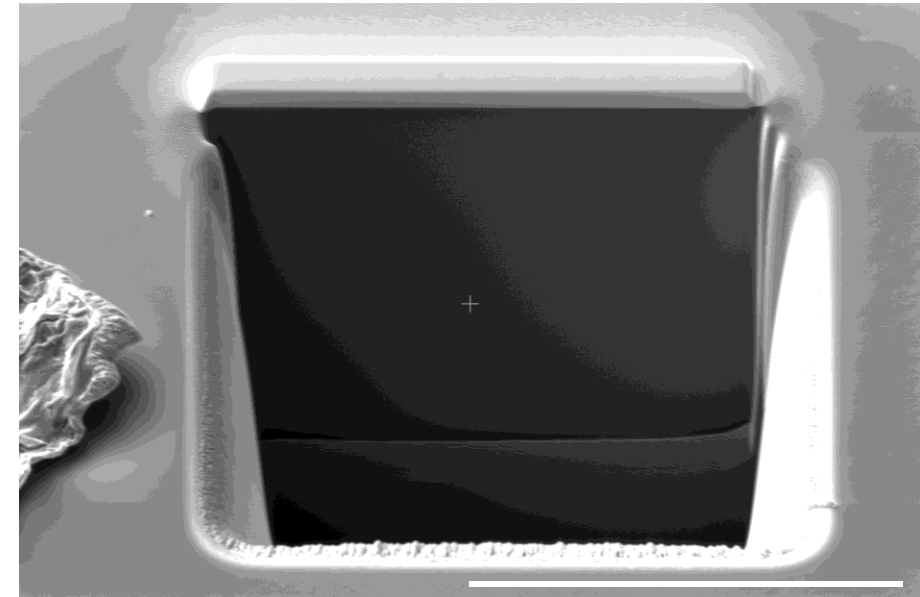
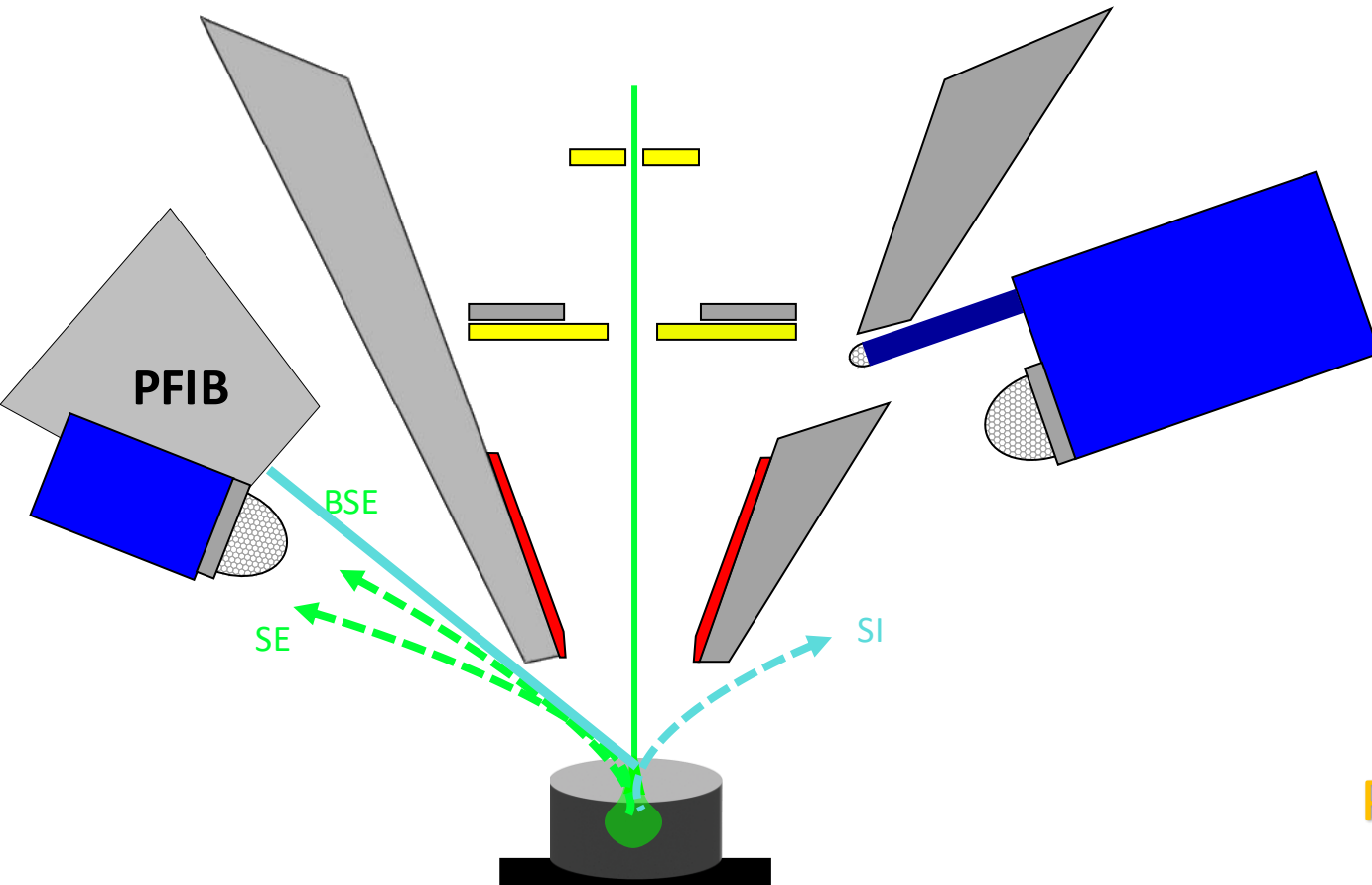


Positive grid bias to attract lower energy SEs

Imaging Detectors

2) Ion Conversion and Electron (ICE) Detector

Ion Beam Induced (SE) Mode

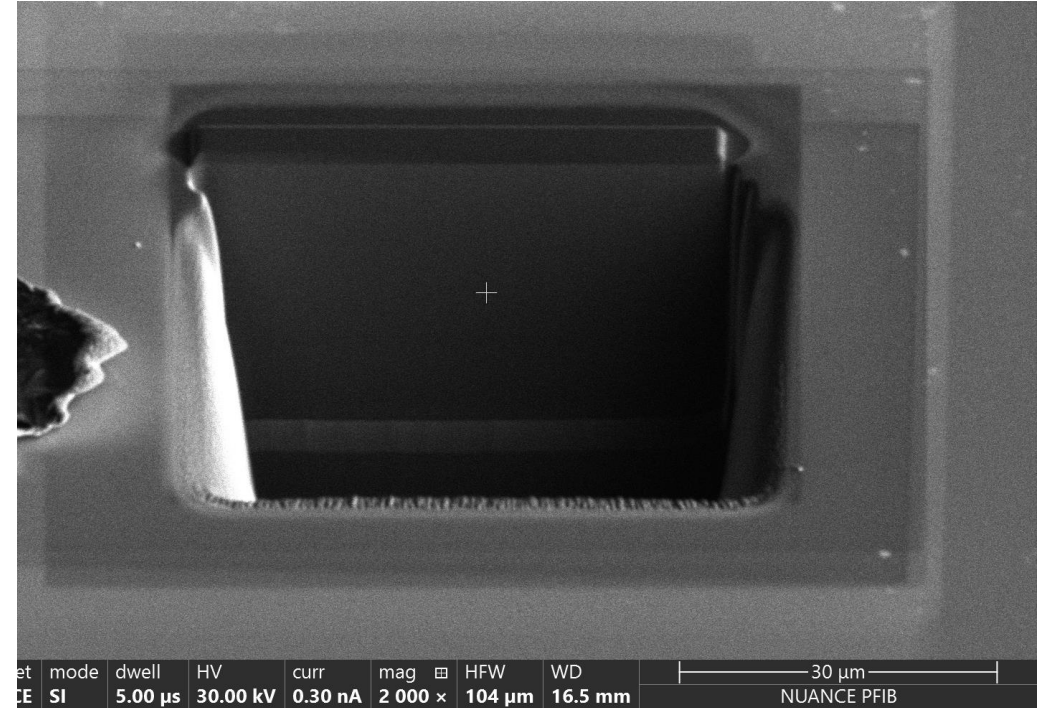
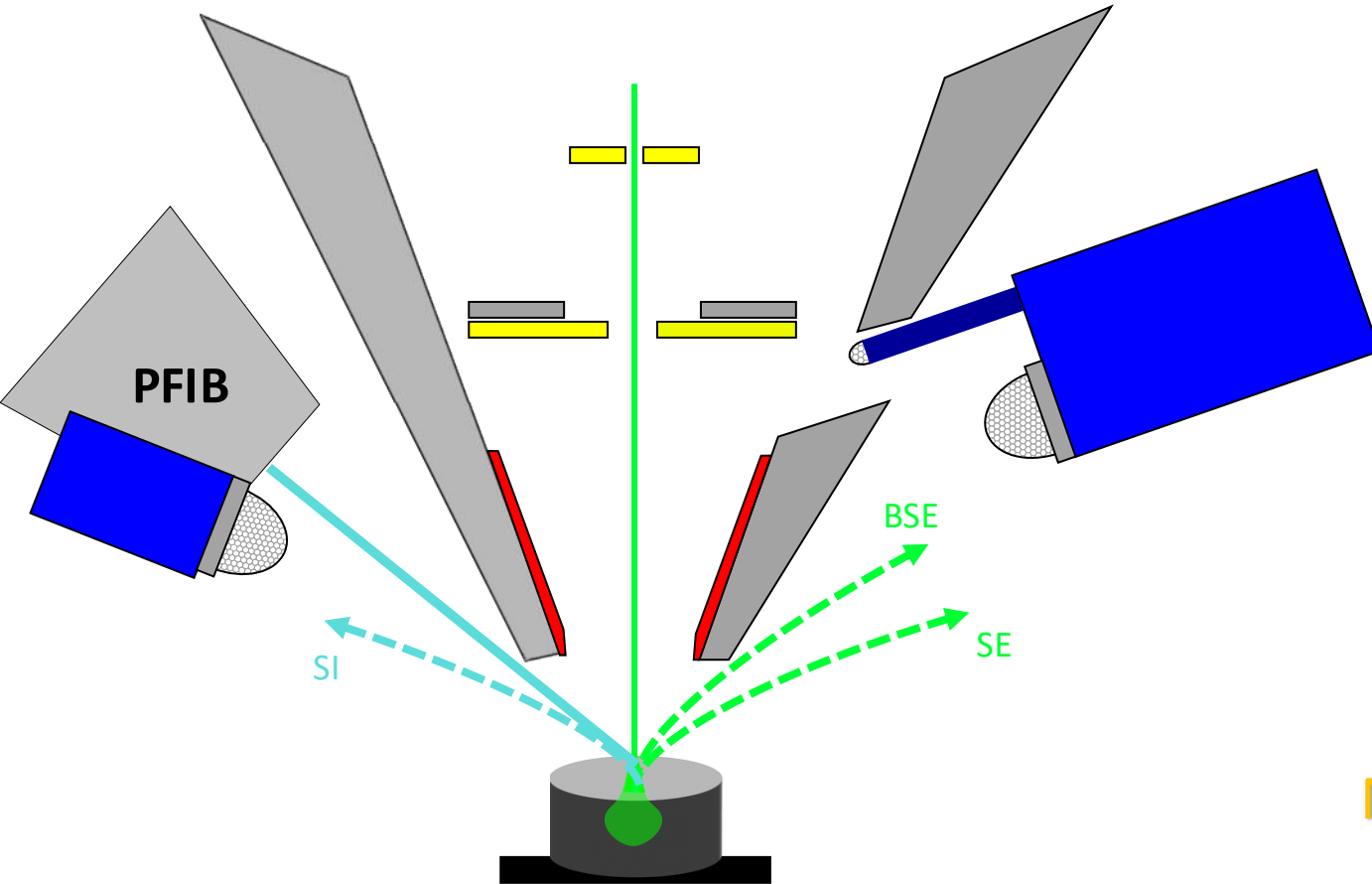


Positive grid bias to attract lower energy SEs

Imaging Detectors

2) Ion Conversion and Electron (ICE) Detector

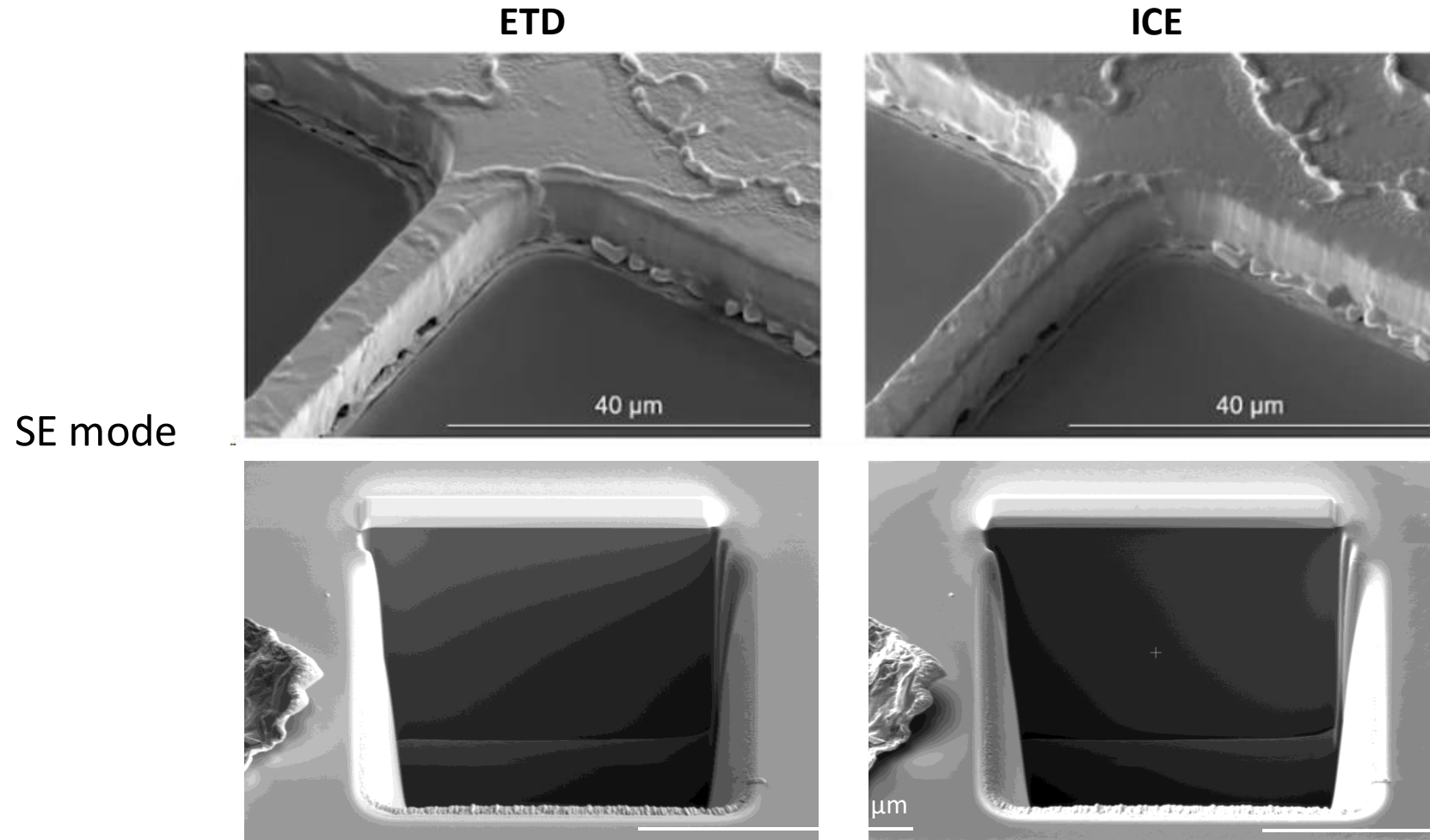
Secondary Ion (SI) Mode



Negative grid bias to attract SIs, repel SEs

ETD vs ICE Detector

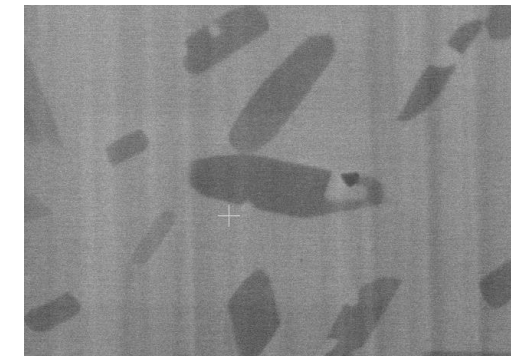
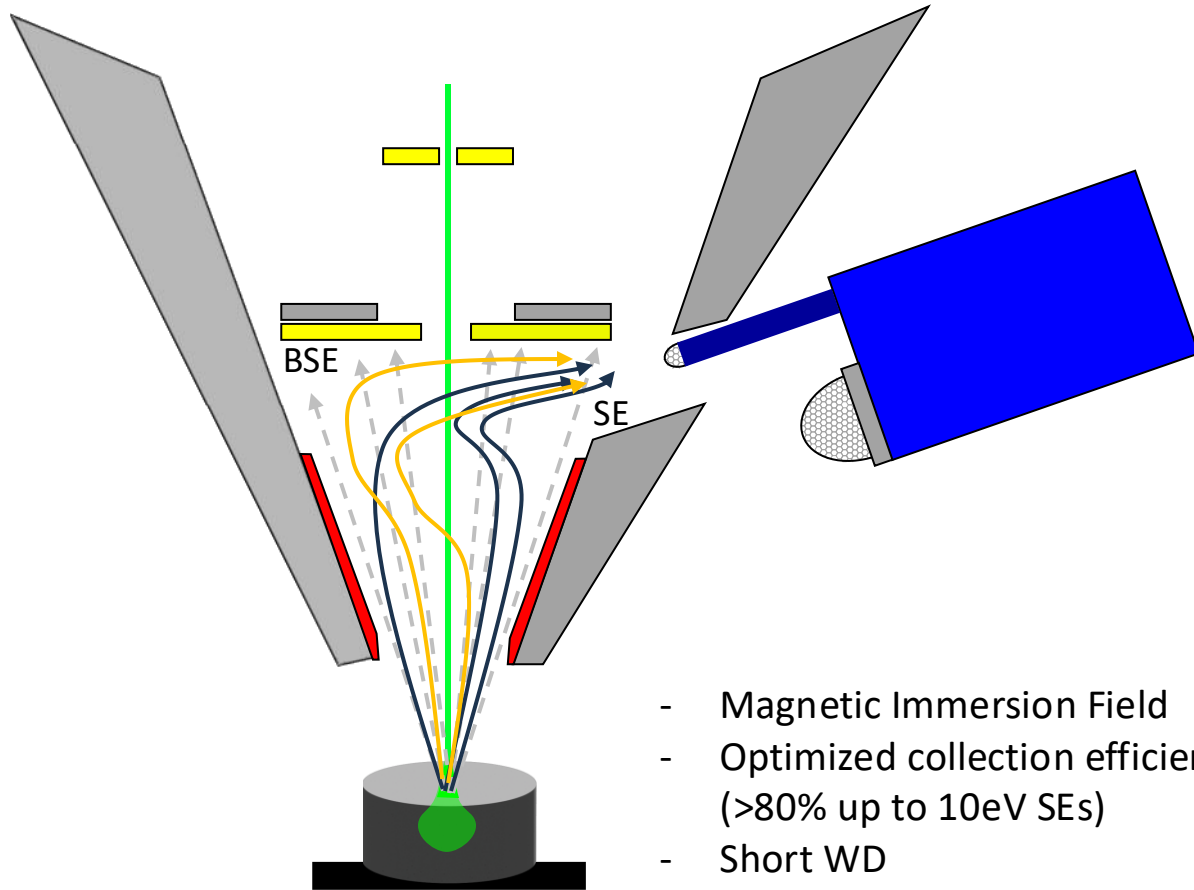
- ICE can be complementary to the ETD
- Simultaneous detector imaging



Imaging Detectors

3) Through Lens Detector (TLD)

Secondary Electron (SE) Mode

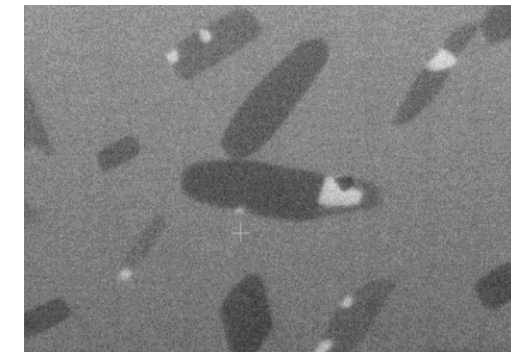
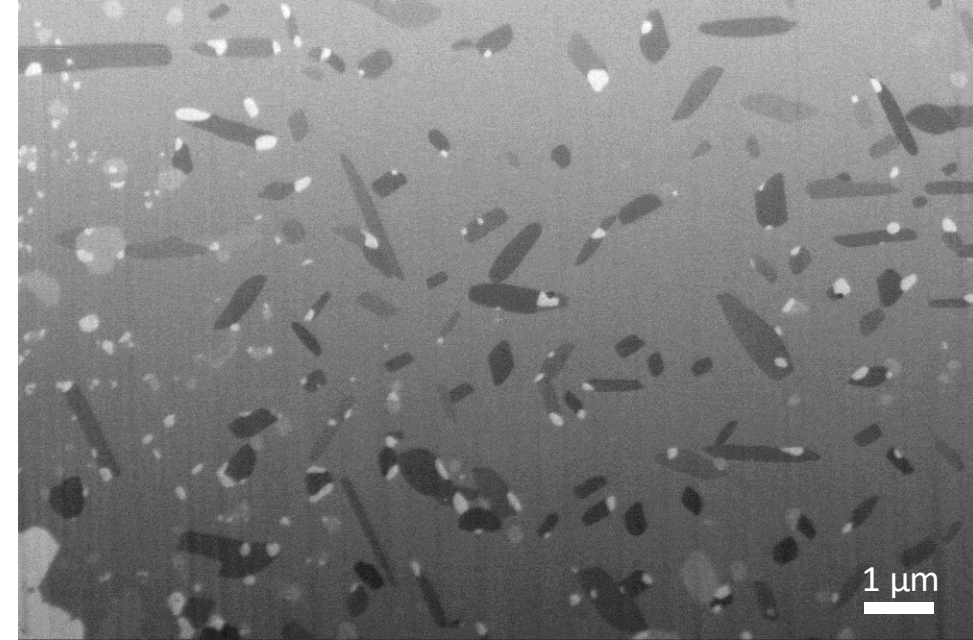
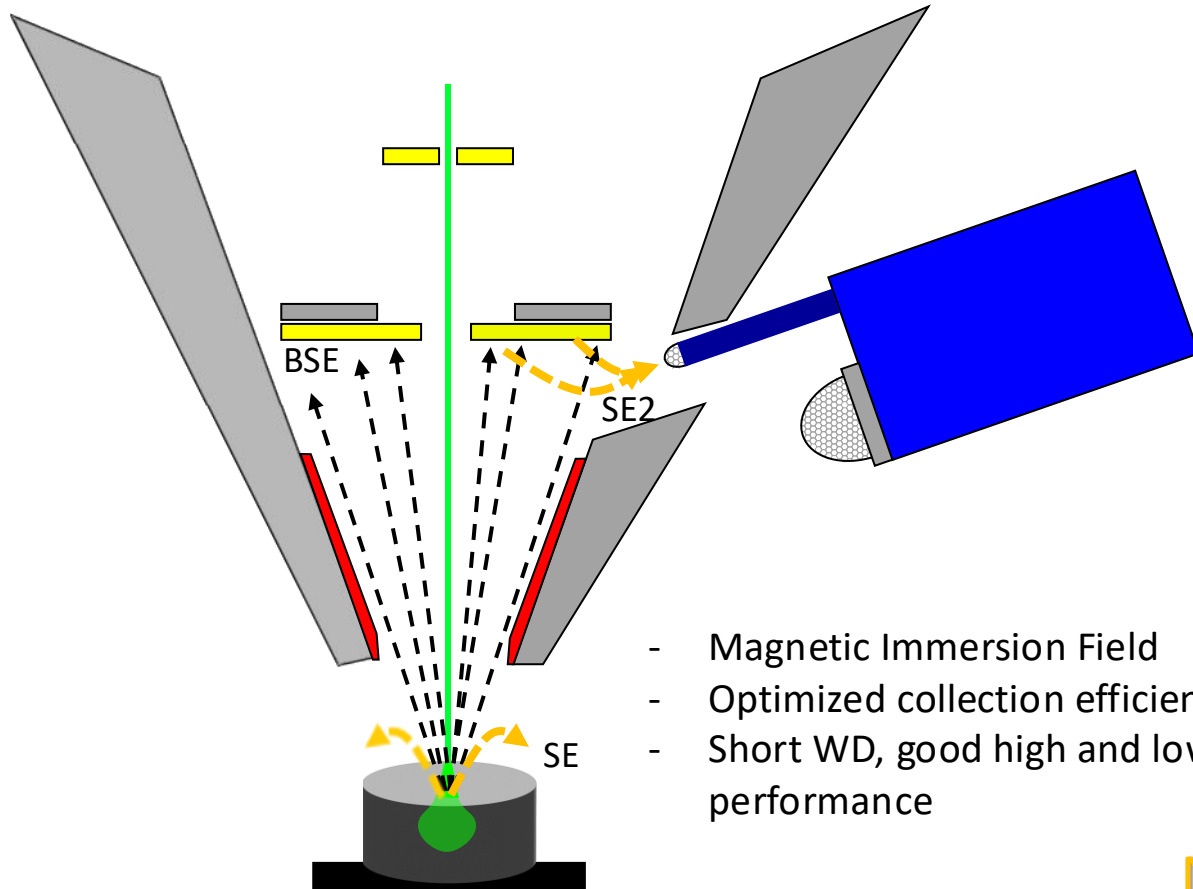


Positive suction tube bias drives SEs into TLD

Imaging Detectors

3) Through Lens Detector (TLD)

Backscatter Electron (BSE) Mode

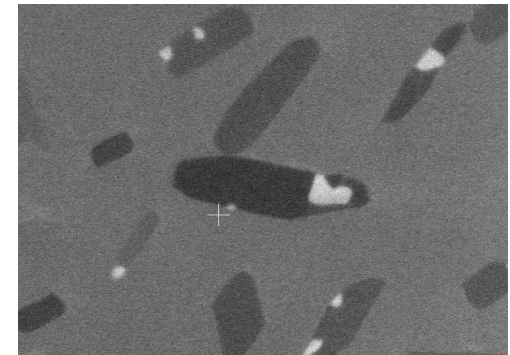
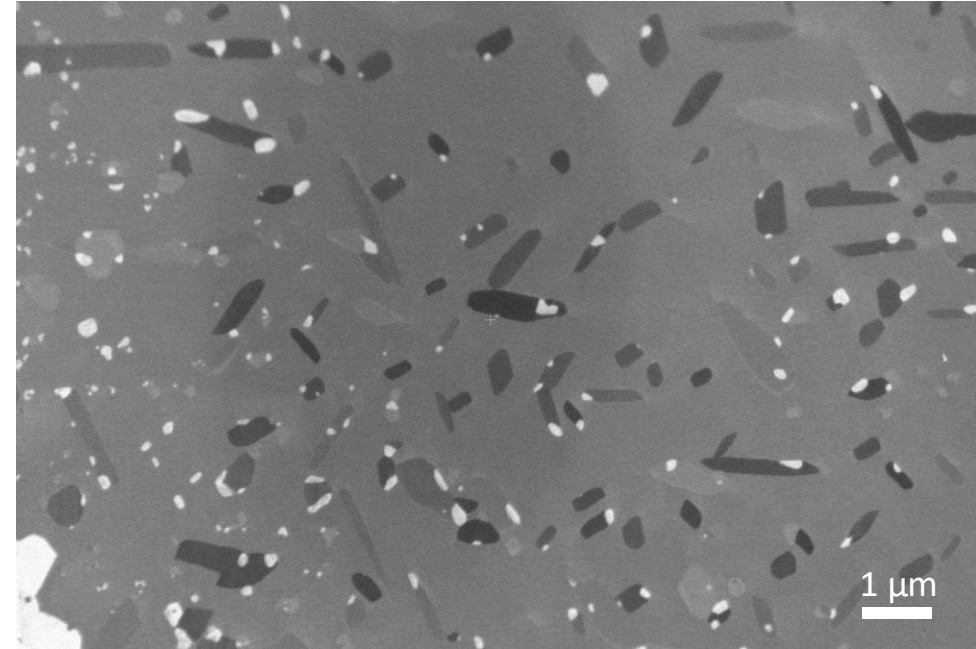
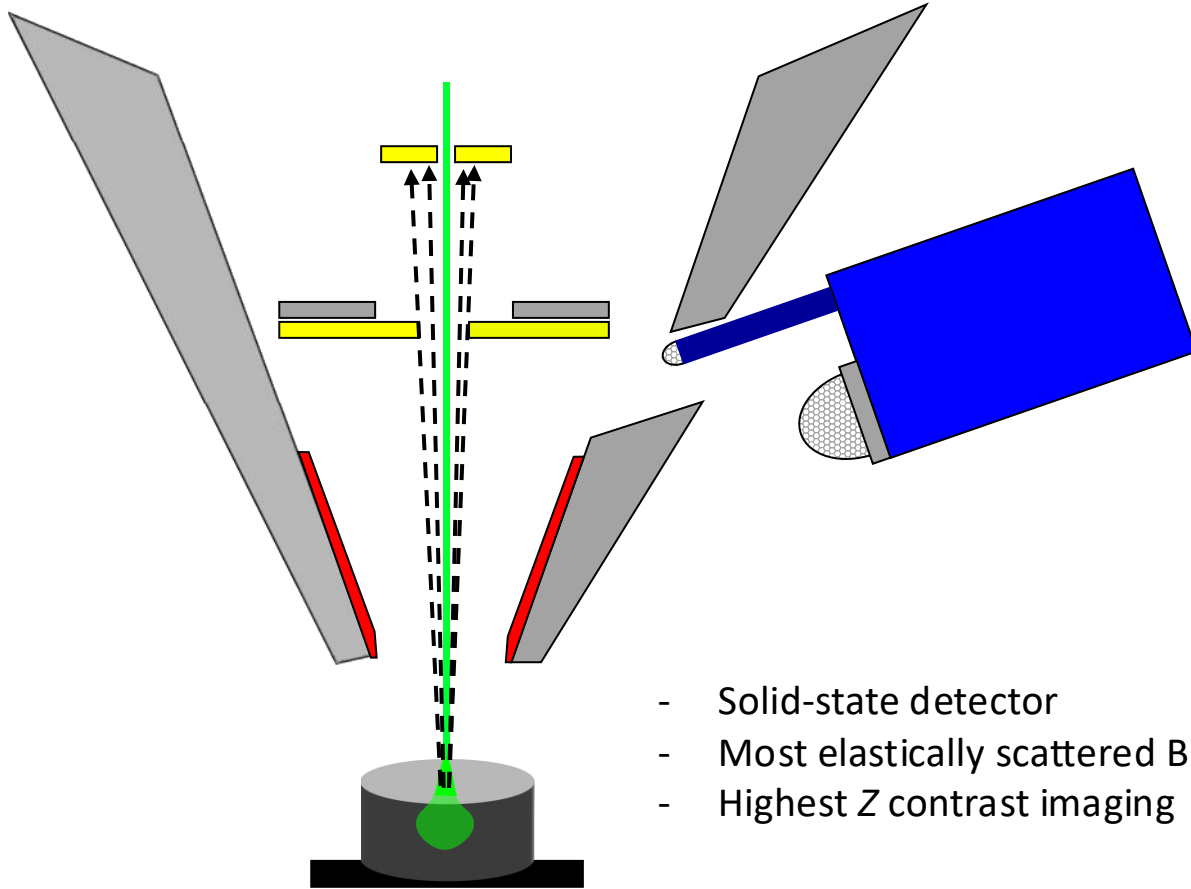


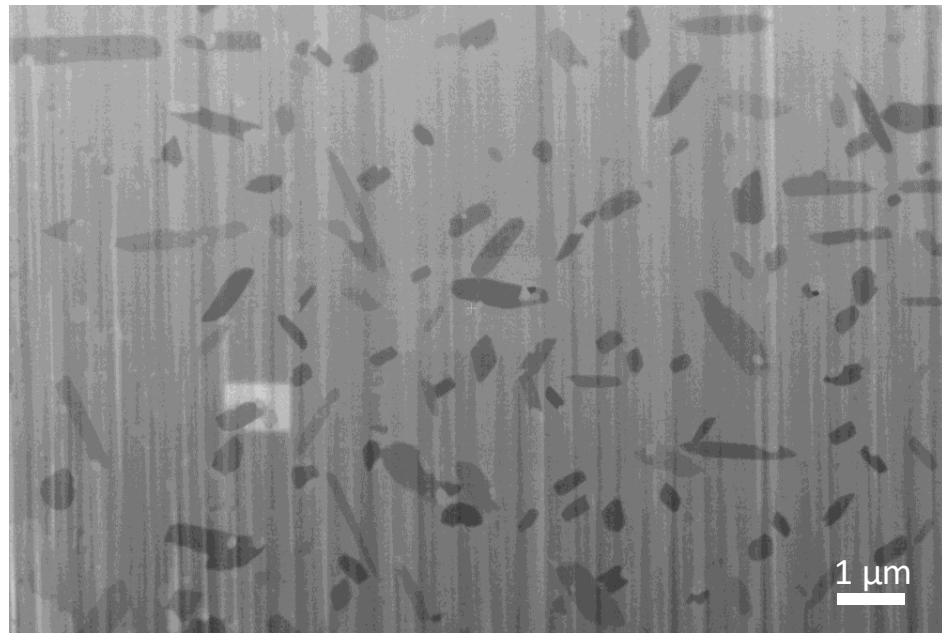
Negative suction tube bias repels SEs, SE2 into TLD

Imaging Detectors

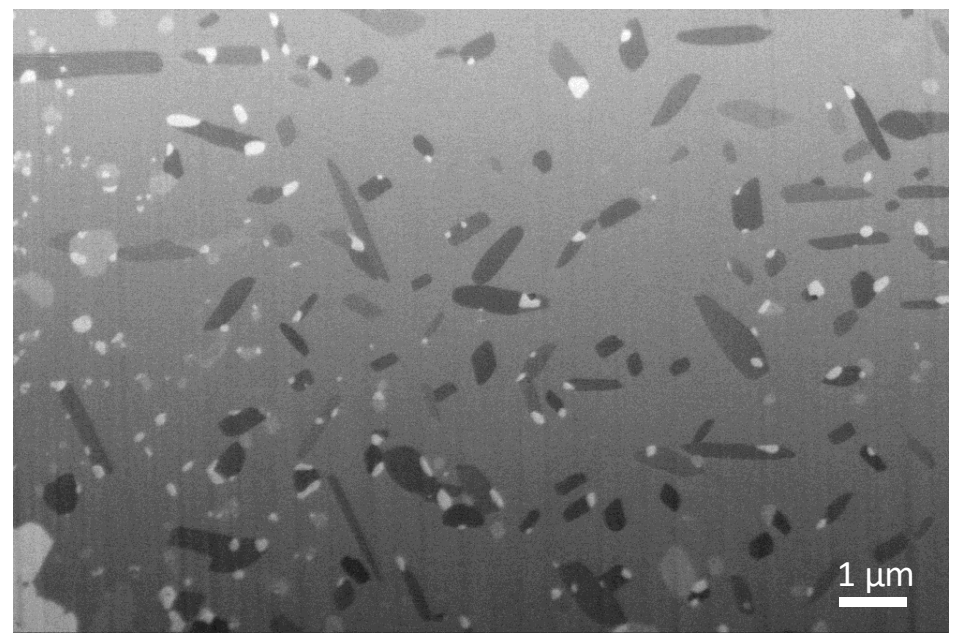
4) In-Column Detector (ICD)

Backscatter Electron (BSE) Mode

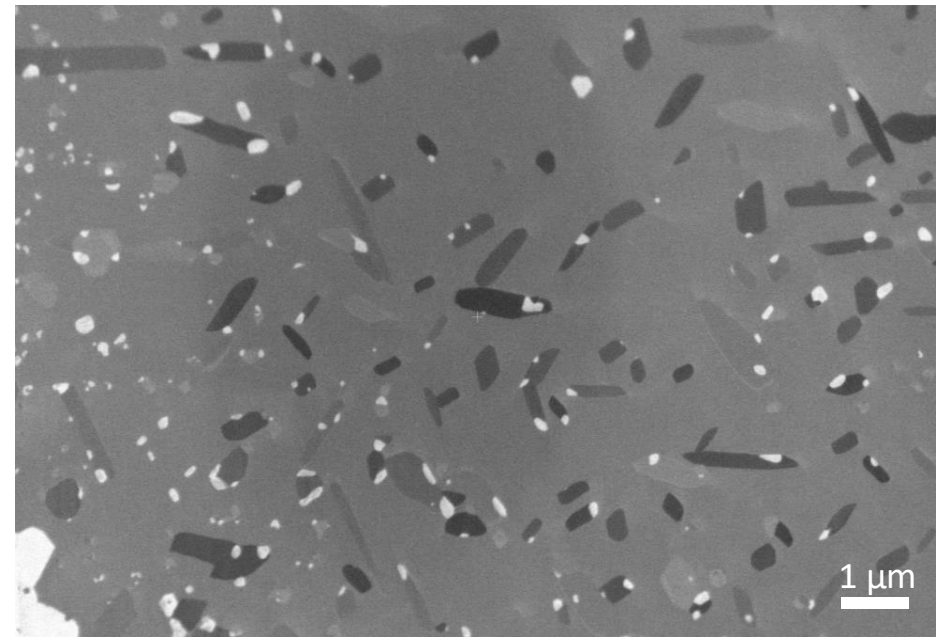




TLD
VS
ICD



most surface topology
No Z contrast imaging
Lowest SNR



least surface topology
Z contrast imaging
Lower SNR

least surface topology
Z contrast imaging
Highest SNR

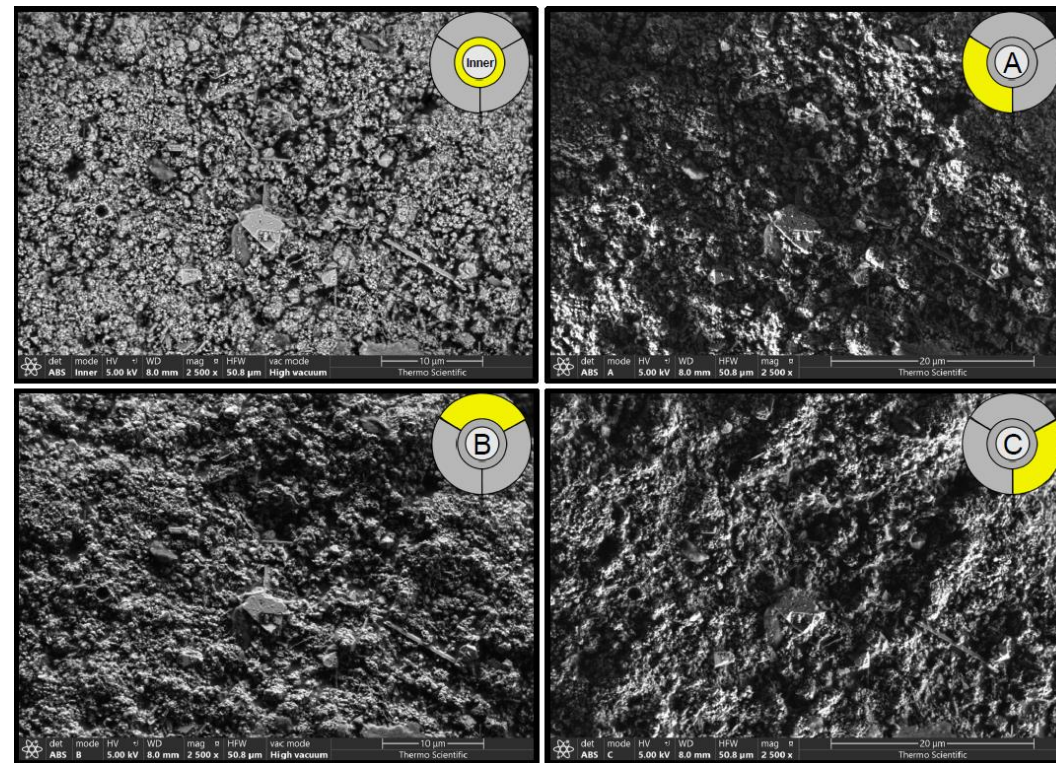
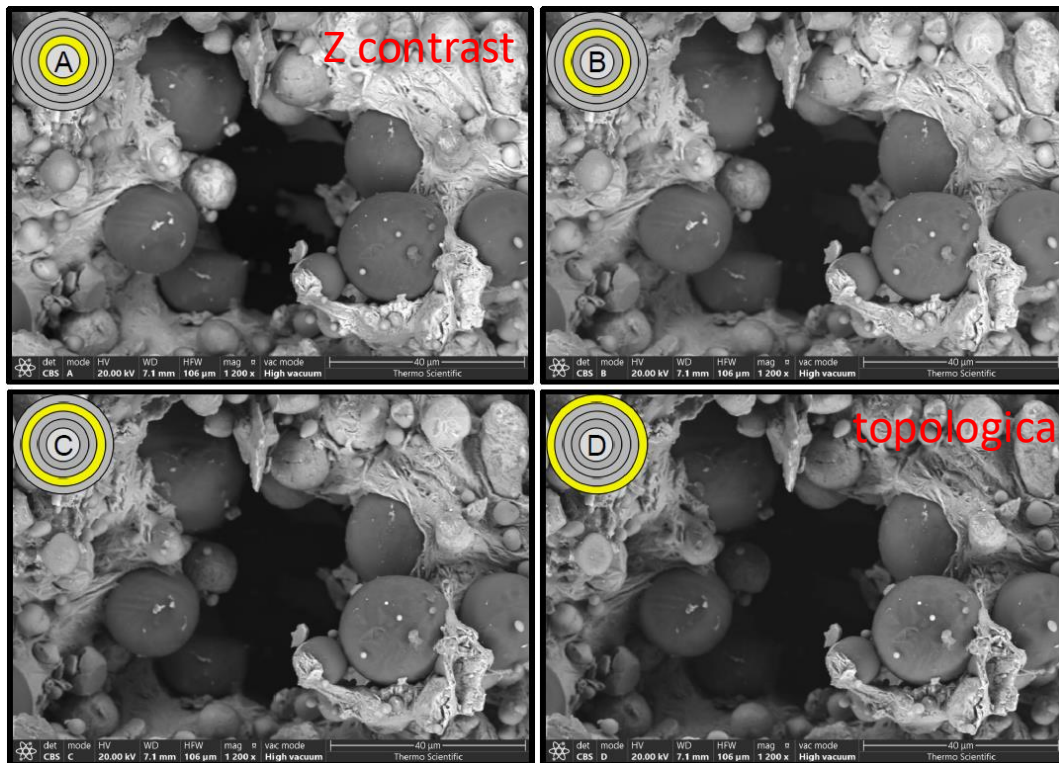
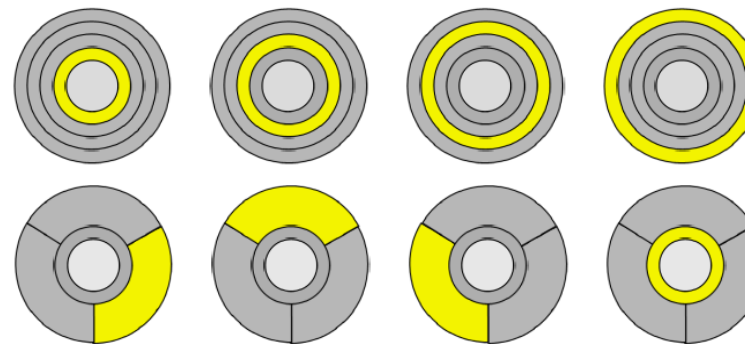
5) Retractable Directional Backscattered Detector (DBS)



Software-based segmentation

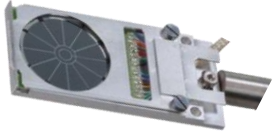
1) Concentric Backscattered Detector (CBD)

2) Angular Backscattered (ABS) Detector

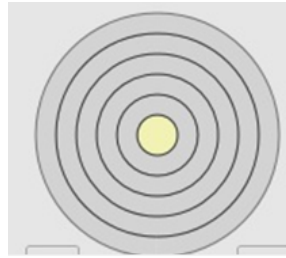


6) Retractable Scanning Transmission Electron Microscopy (STEM)

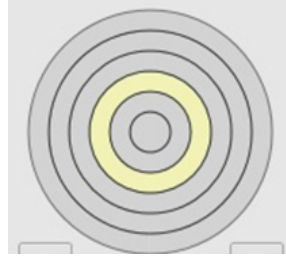
Detector



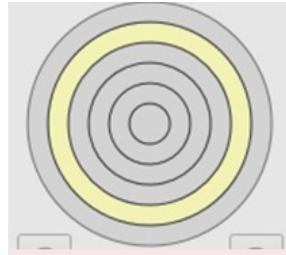
Pre-tilted row holder & STEM image



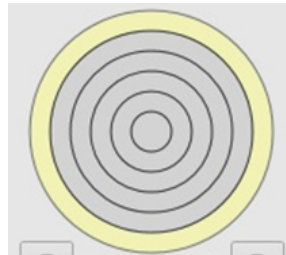
1) Bright Field (BF)



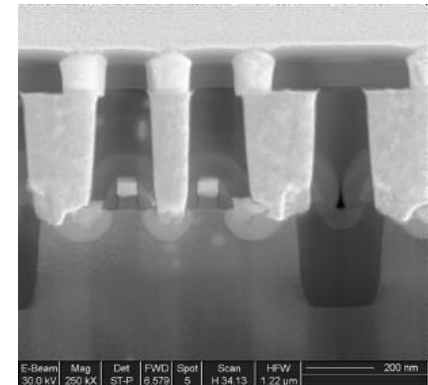
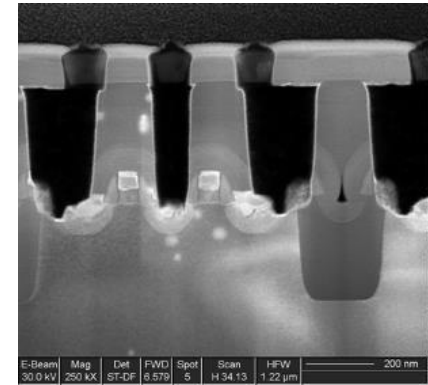
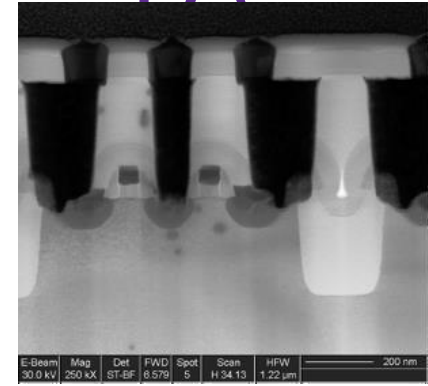
2) Dark Field 2 (DF 2)



3) Dark Field 4 (DF 4)



4) High Angle Annular Dark Field (HAADF)

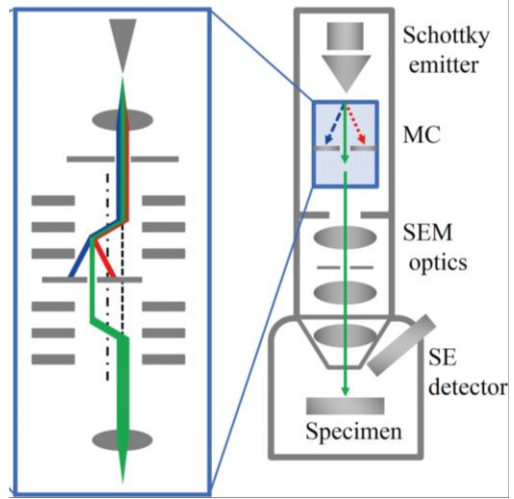


SEM Column Specs – Ultrahigh Resolution Imaging

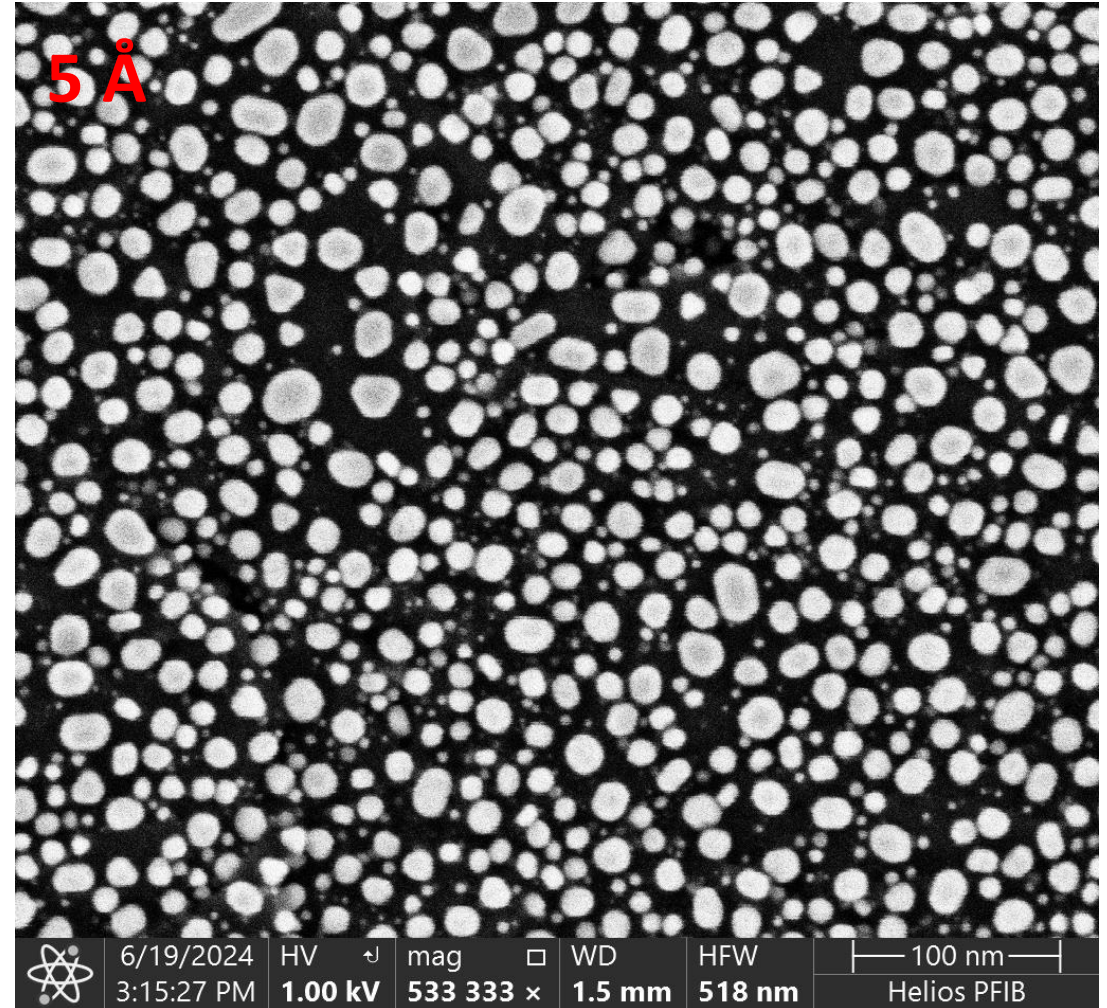
1) UC (monochromated) mode

< 5 kV; < 100 pA

Energy spread
< 0.2 eV

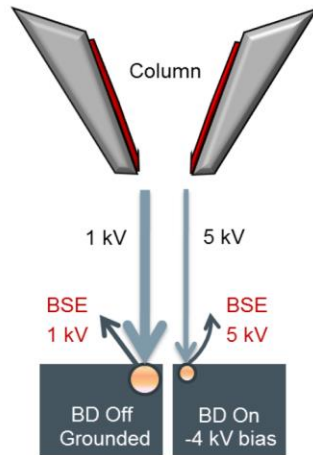


3) Immersion mode/TLD detector: Au on C



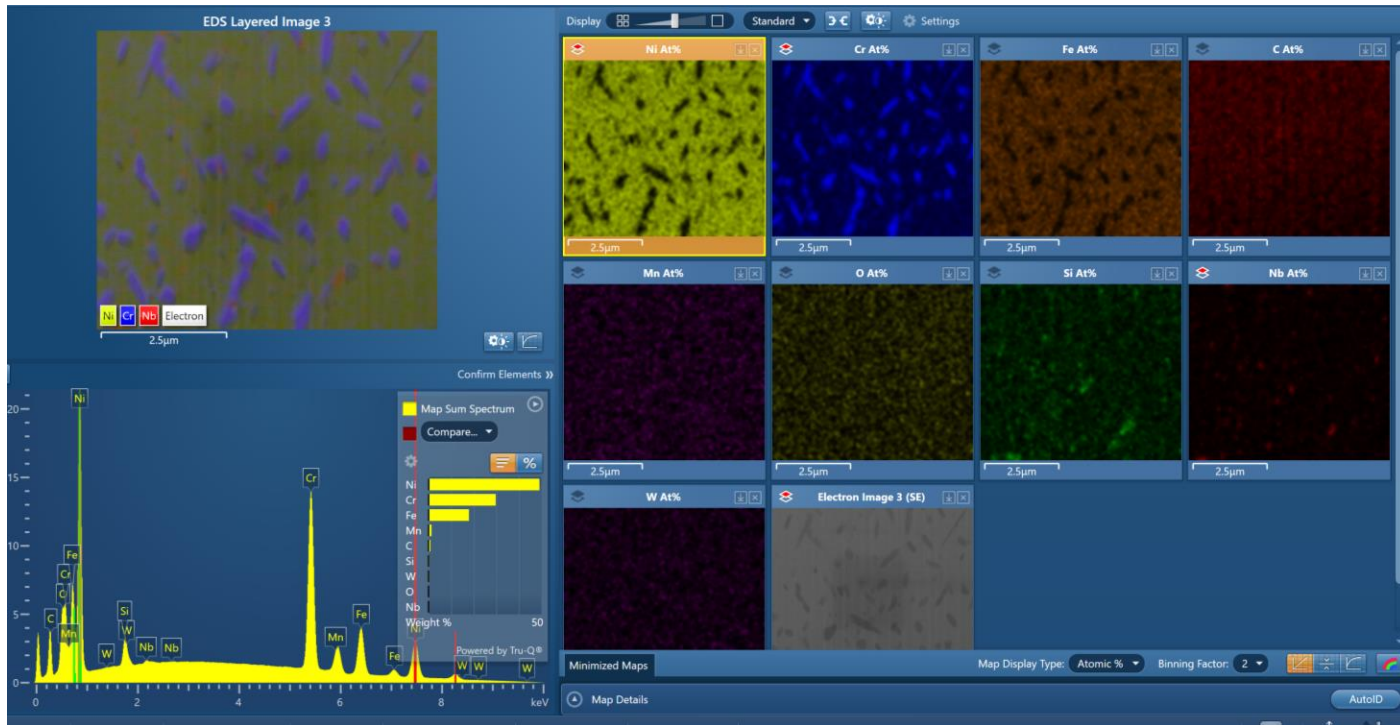
2) Beam Deceleration

Down to 50 eV



Analytical Detectors

Oxford Instruments Ultim Max 100 mm² EDS detector

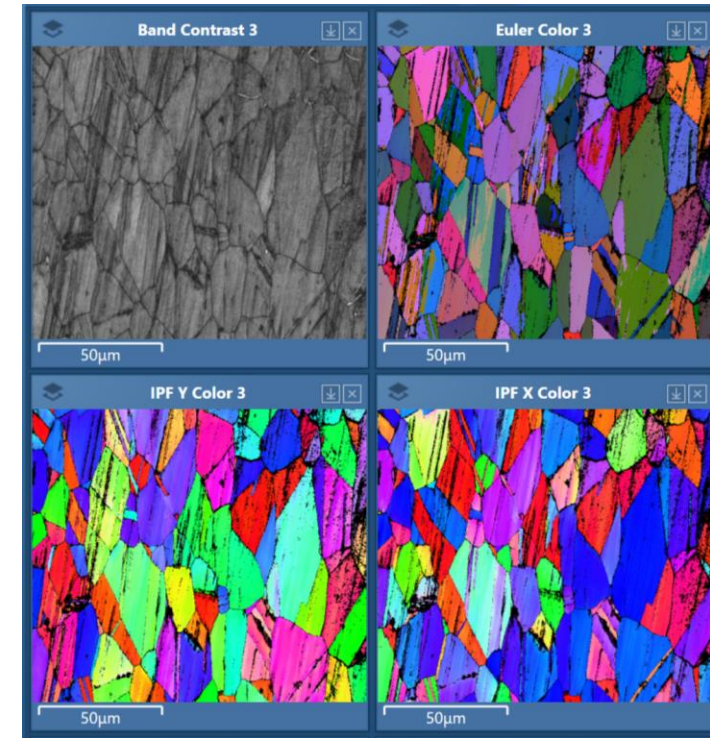


Oxford Symmetry S3 EBSD detector



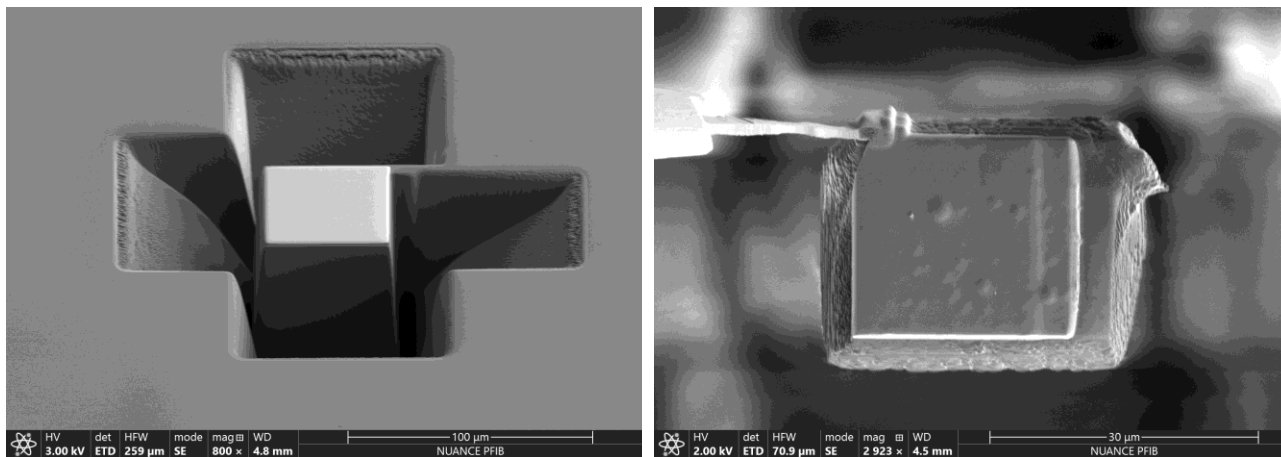
High speed data acquisition:
~5800pps @
156 × 128 px
EBSP

85% ESBP

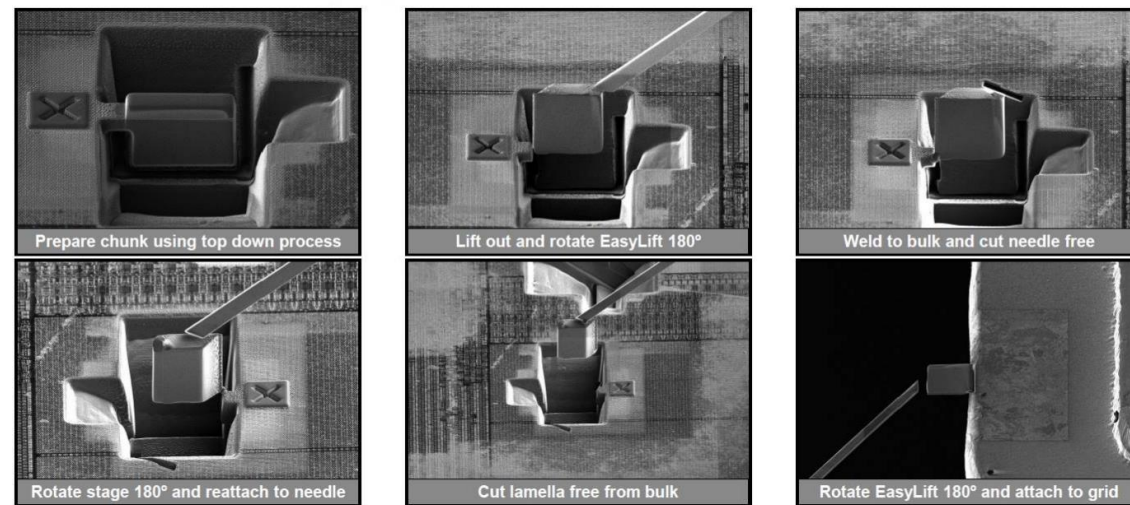


Micromanipulator (“Easylift”) with Rotation

- Resharpen micromanipulator
- Liftout of large volumes; rotation adjustment for attachment to support

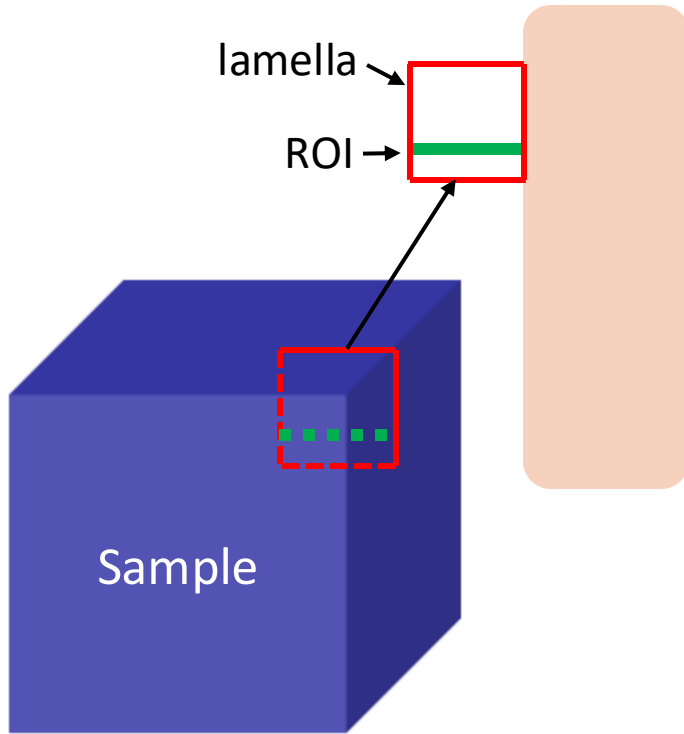


- Flexible TEM sample prep
easier access to plan view sample preparation
and inverted lamella



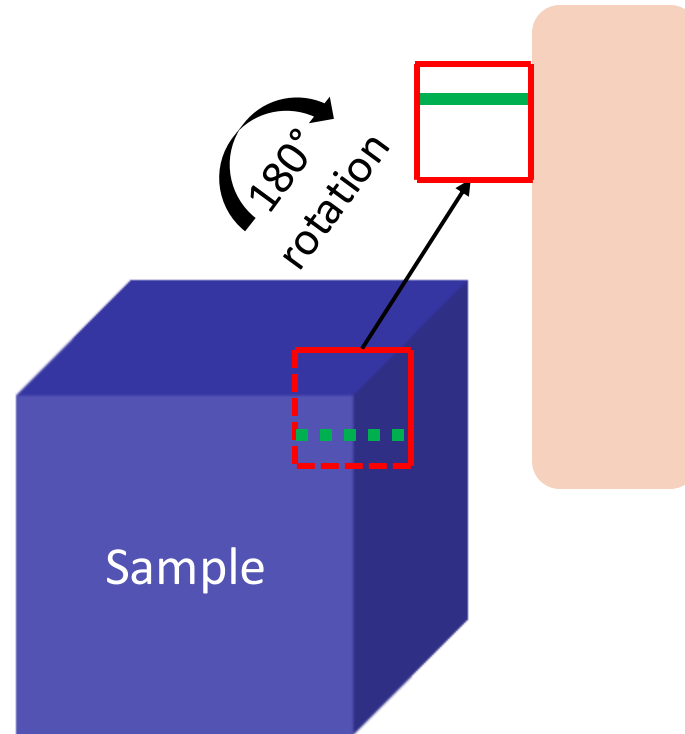
TEM Sample Prep Configurations

Conventional (Top Down)



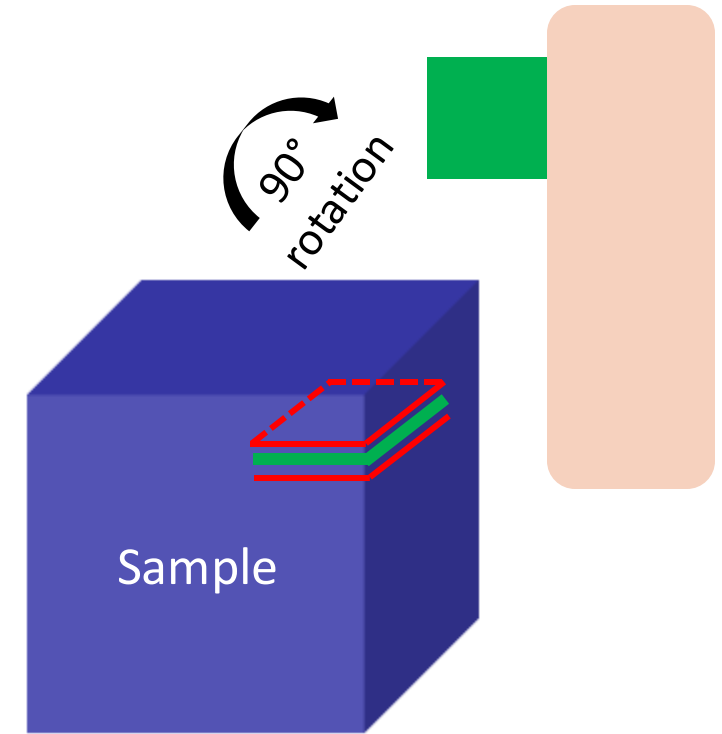
Direct transfer of lamella from bulk to grid

Inverted



Lamella flipped 'upside down' from bulk to grid

Plan View

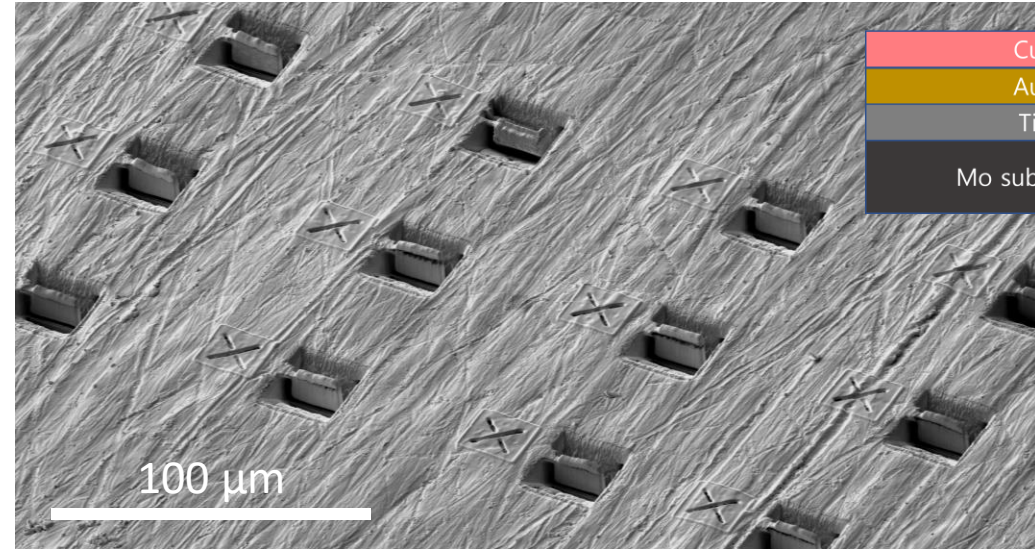
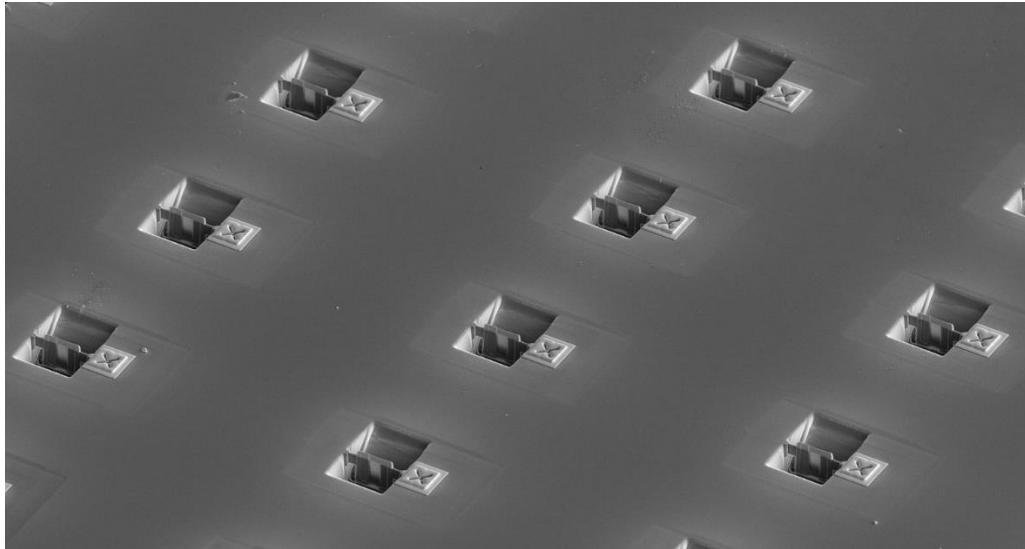
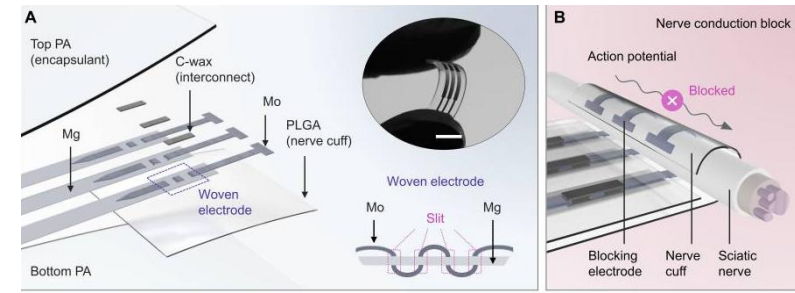


Lamella is rotated 90° where ROI is parallel to bulk surface

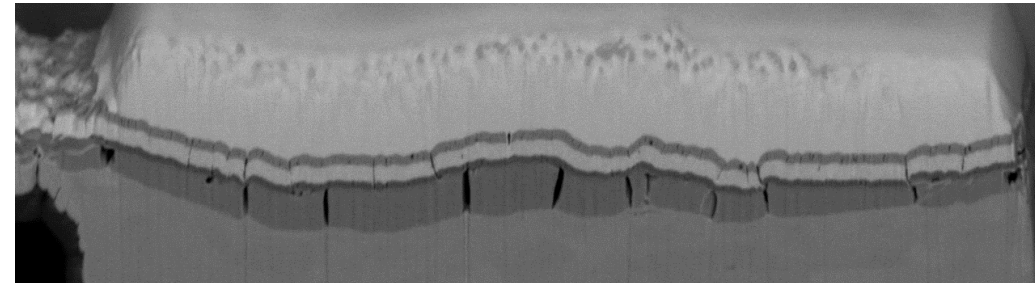
Available Thermo Fisher Software

- **AutoTEM 5** – automated, high productivity creation of high quality (S)TEM sample preparation
- **Auto Slice & View 5** - Automated FIB serial sectioning software with 3D EDS and 3D EBSD capability
- **MAPS 3** - Correlative electron microscopy and cross-platform imaging automation software
- **Avizo 3D** - Software for microscopy image data visualization and analysis

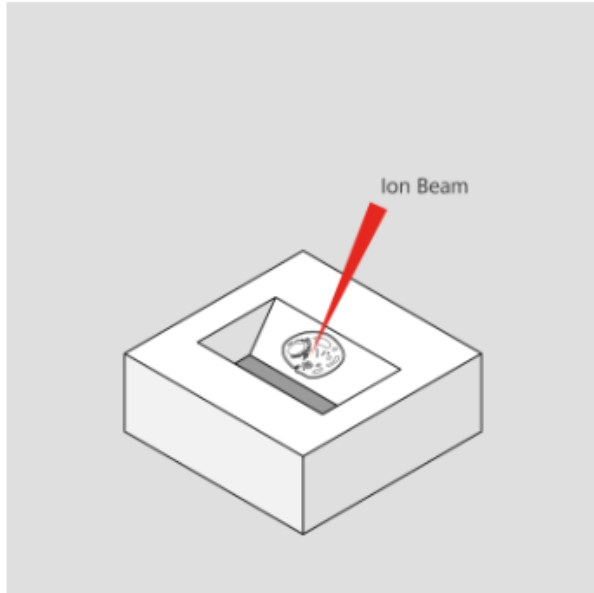
AutoTEM 5



12 TEM lamella in 7 hrs

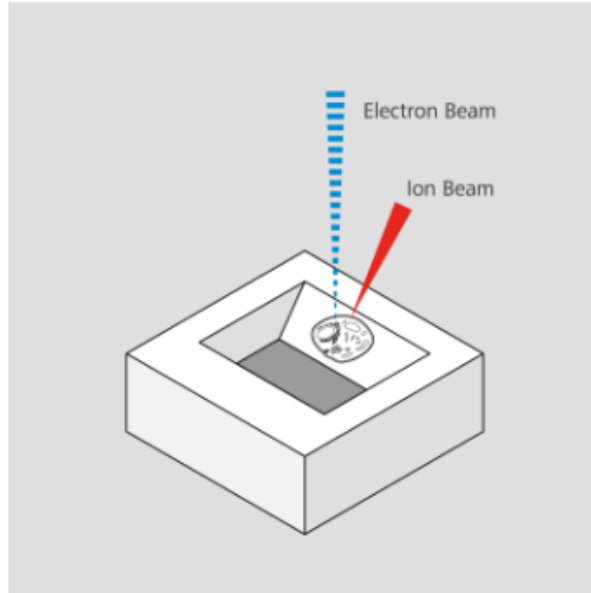


Auto Slice & View 5



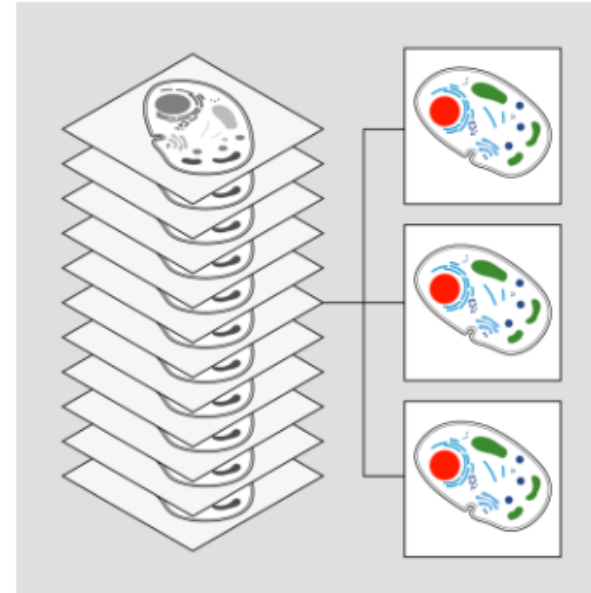
1

A trench is milled into a resin-embedded sample with a focused ion beam until the structure of interest becomes visible.



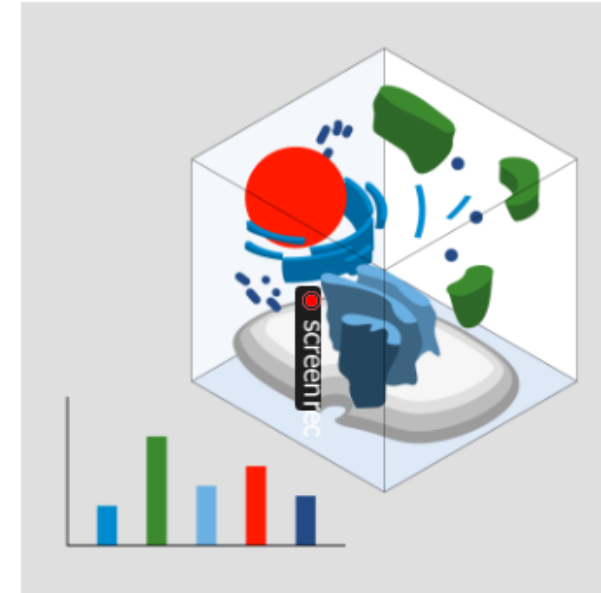
2

The newly exposed sample surface of the structure of interest is imaged. This milling and imaging process is repeated until the structure is completely imaged.



3

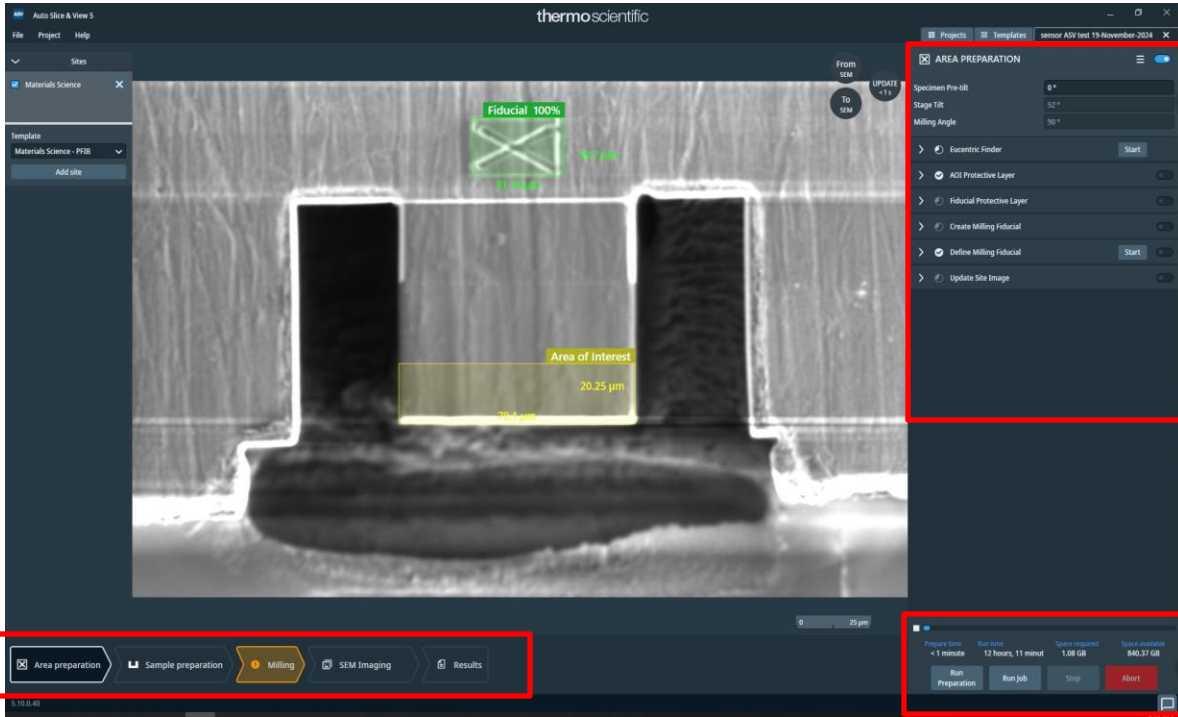
The acquired EM images are processed and digitally aligned into a 3D data set. Cell compartments can be identified and segmented.



4

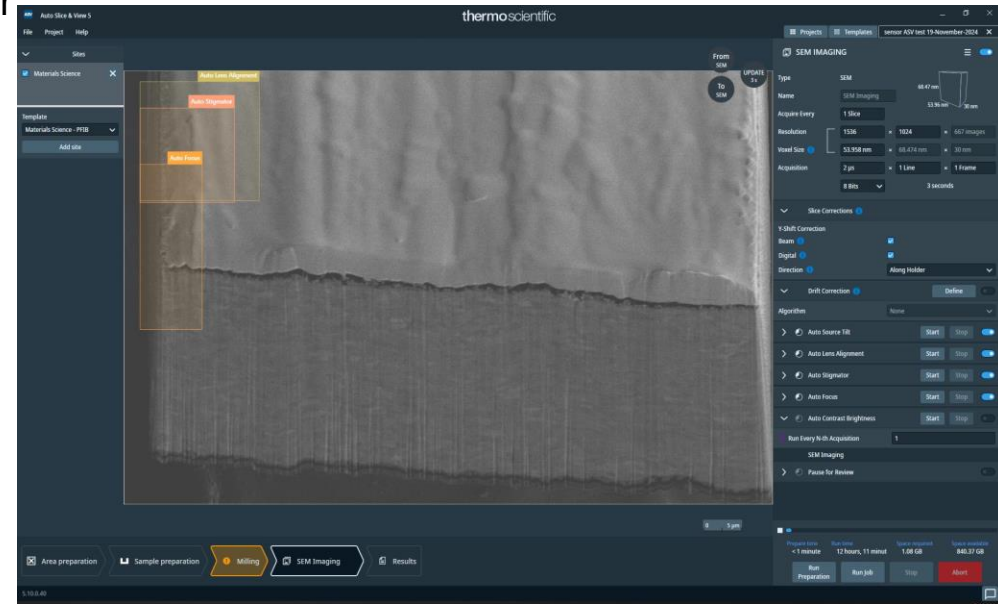
The segmented 3D data set can be visualized, investigated, and statistically analyzed.

Auto Slice & View 5



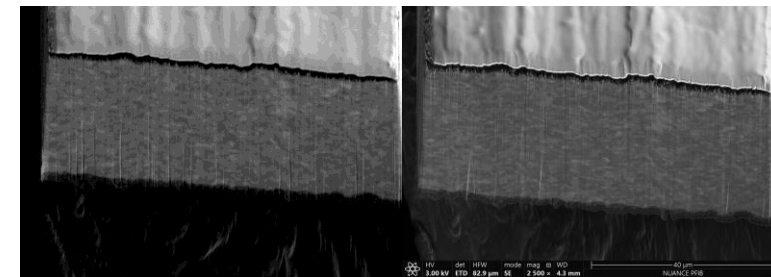
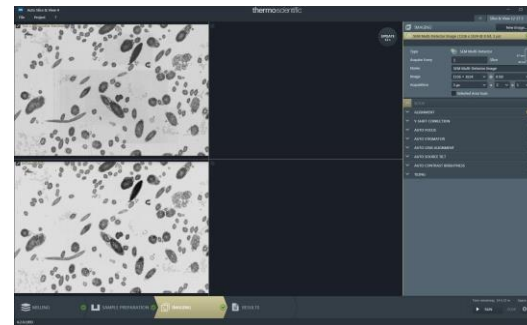
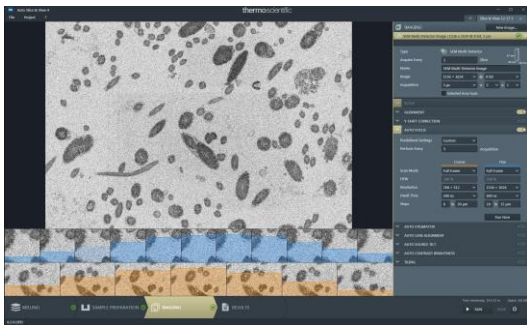
Parameters for each step

Progress



Workflow

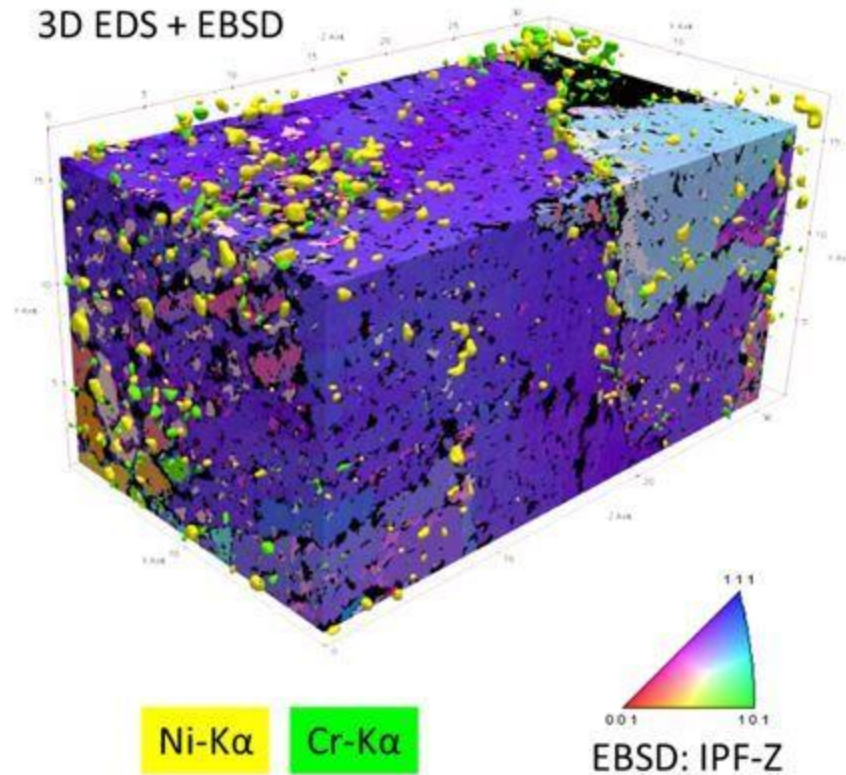
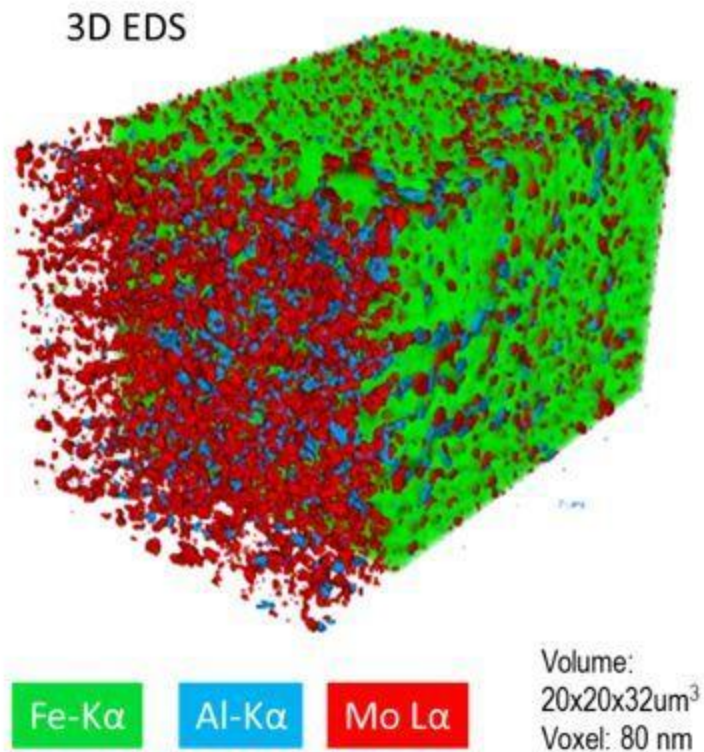
- Autofocus and autostigmation strategies
- Simultaneous Multiple detector imaging
- Rocking step for decreasing curtaining



... and much more!

Auto Slice & View 5; 3D EDS & EBSD

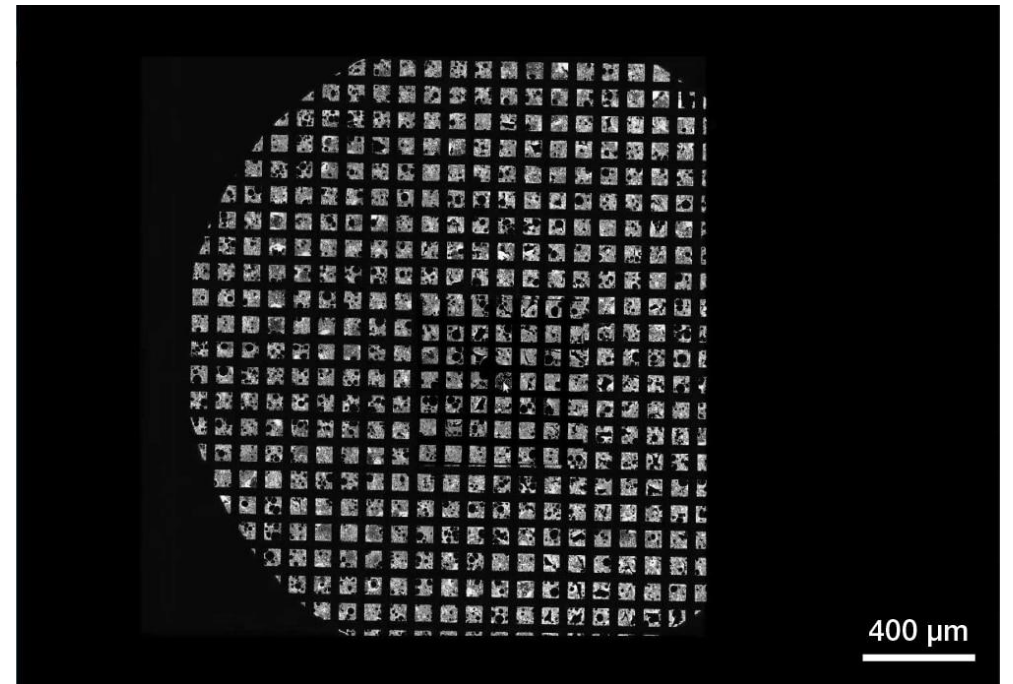
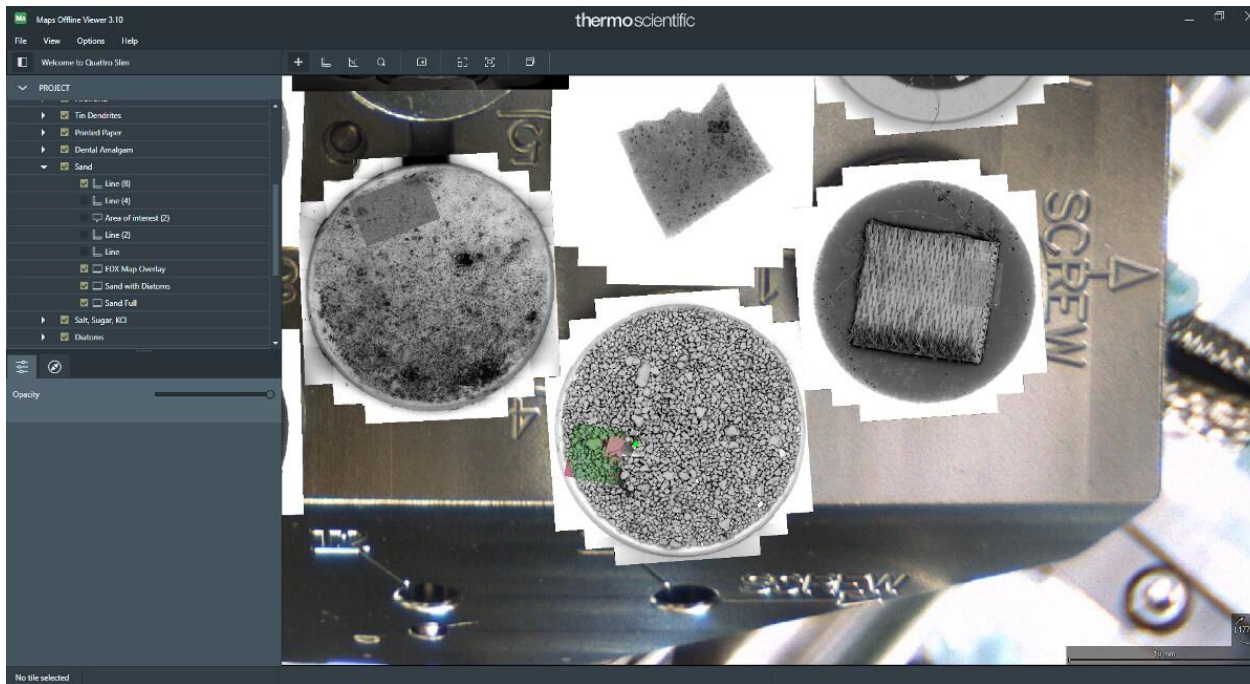
Multimodal analysis in three dimensions



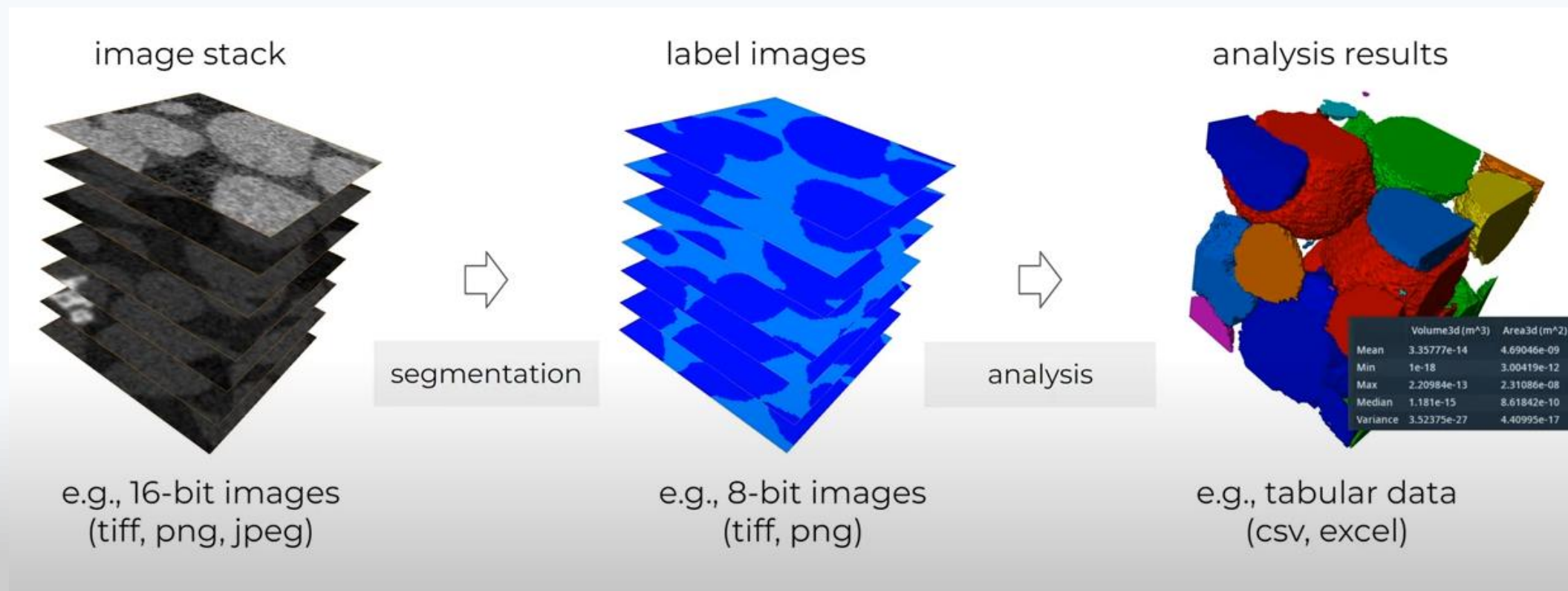
Sample from Ecole Polytechnique in Montreal

MAPS 3

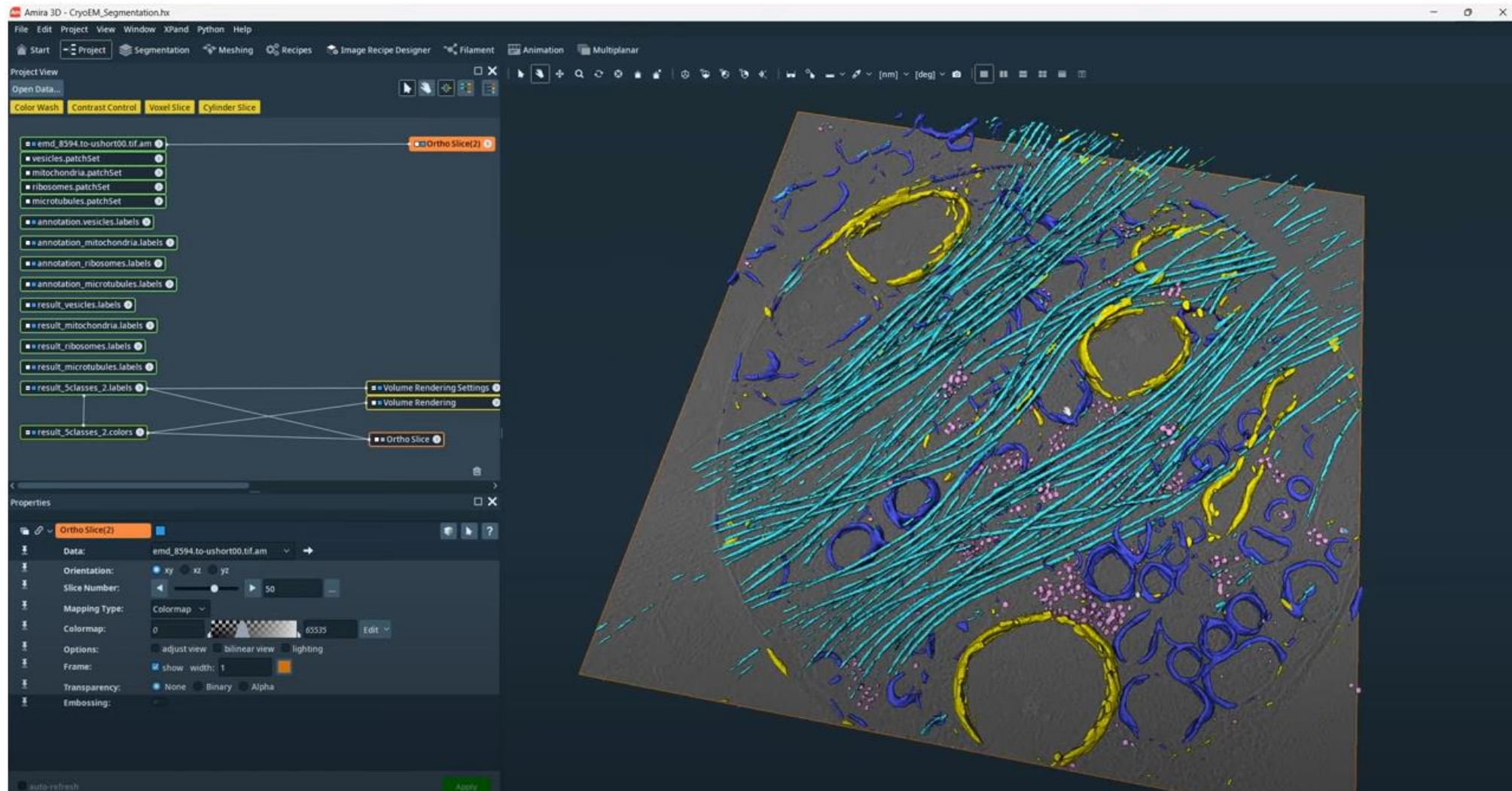
- Correlative (optical) imaging and FIB-SEM image stitching



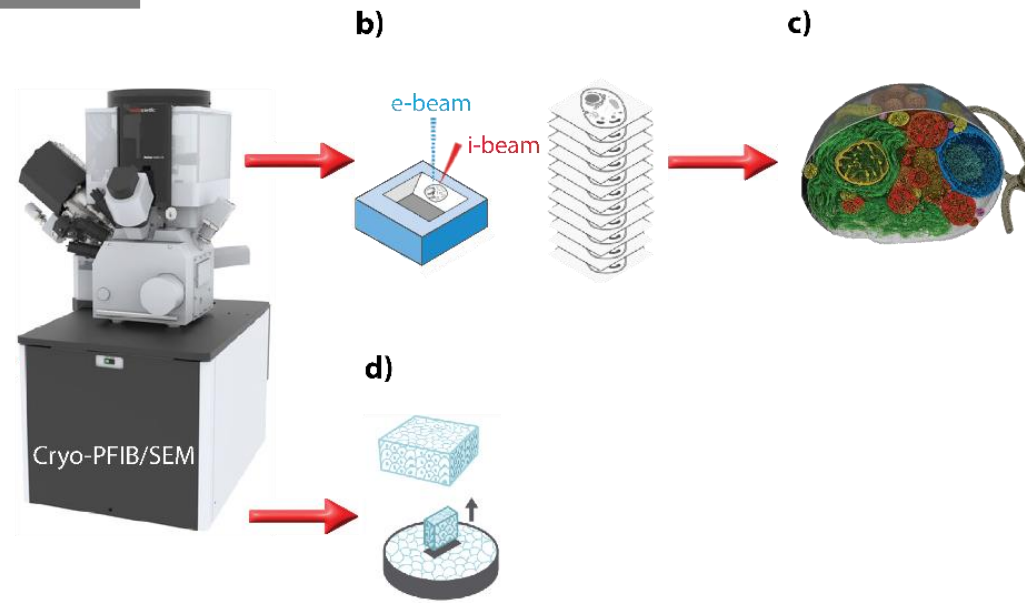
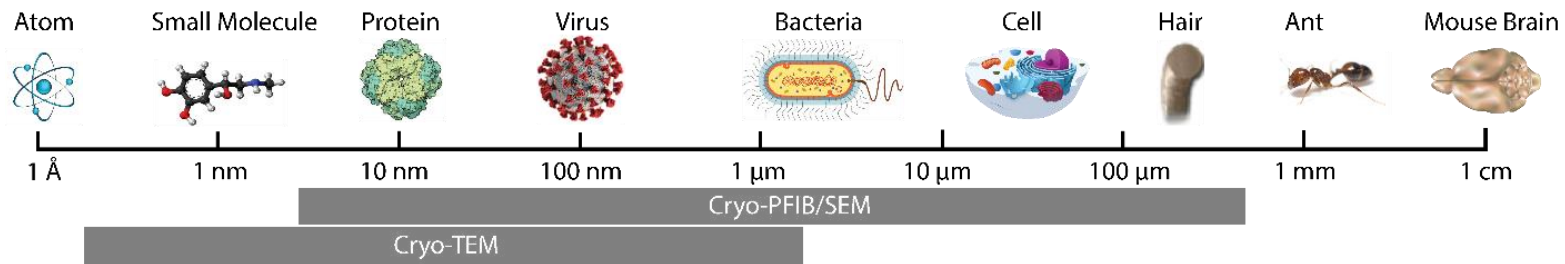
Avizo 3D



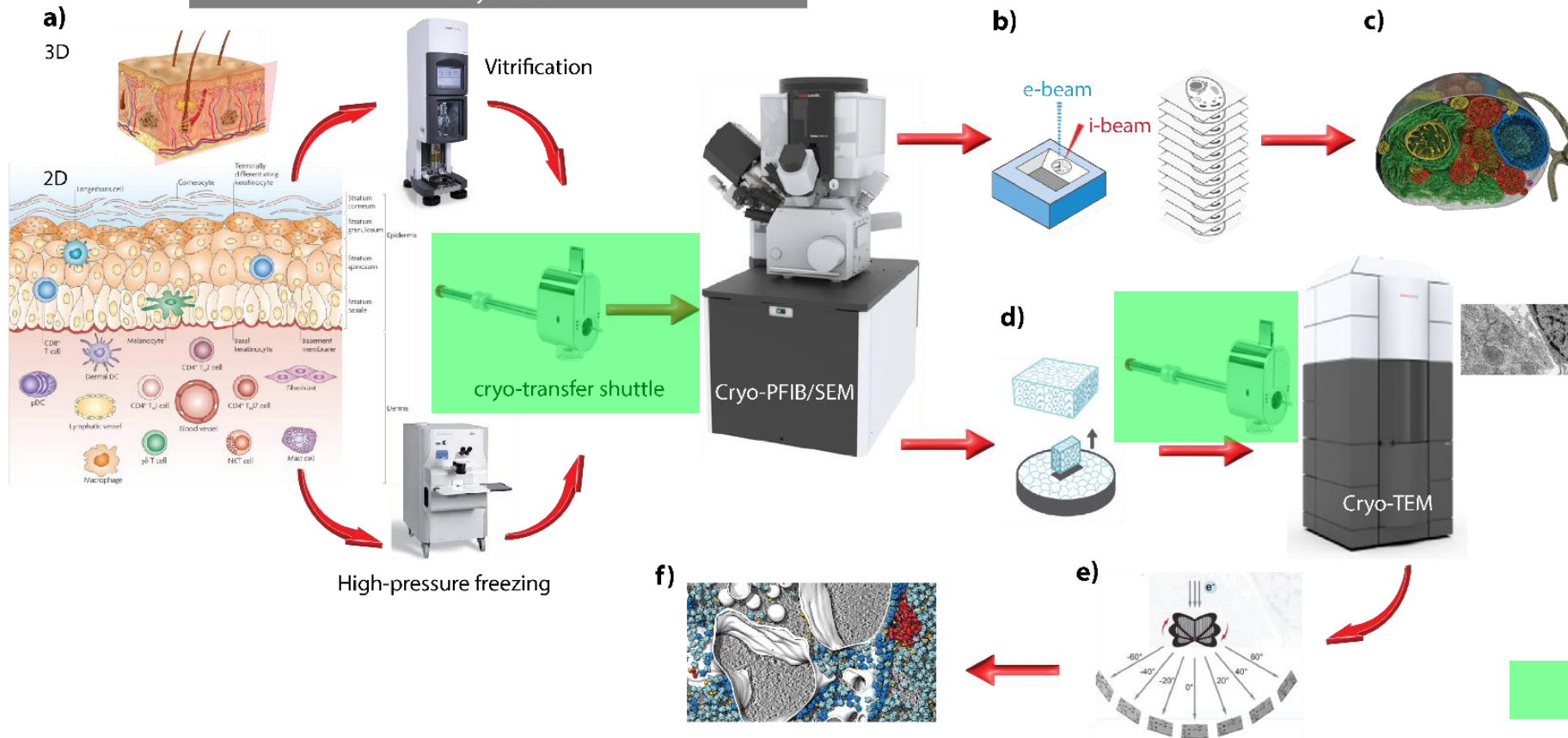
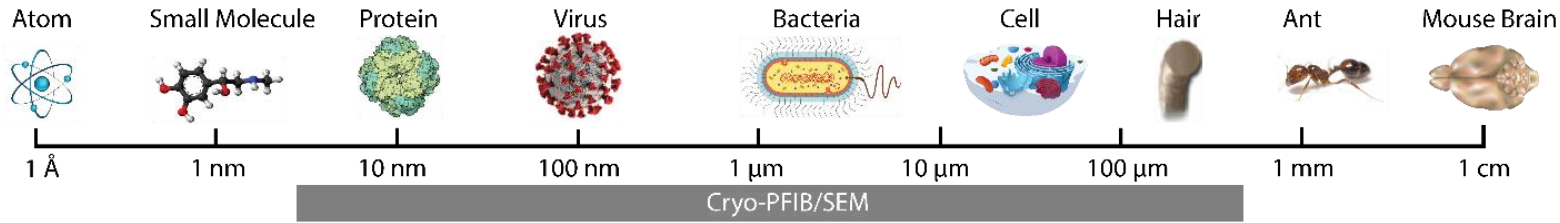
Avizo 3D



Cryo-PFIB/SEM

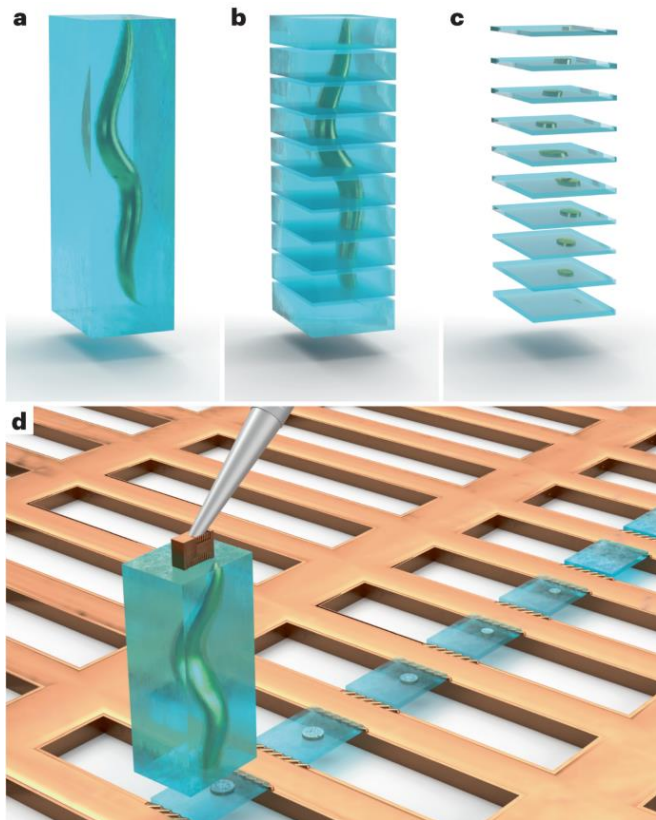


Cryo-PFIB/SEM

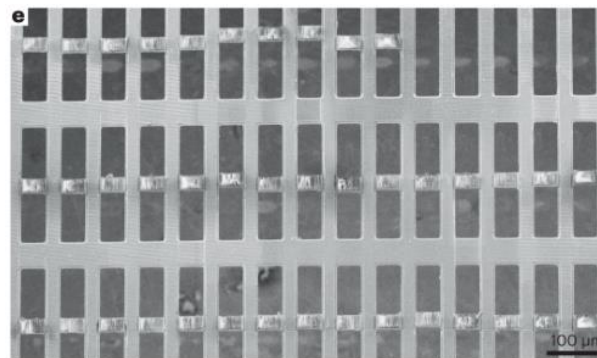


Cryo-PFIB/SEM

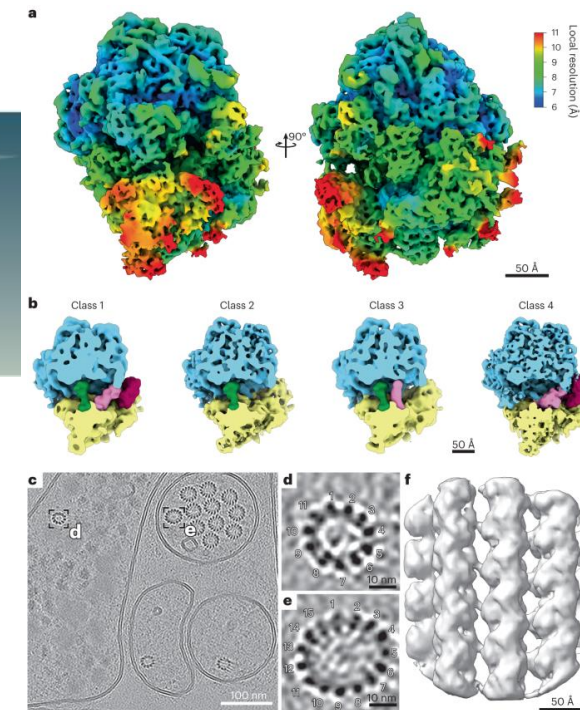
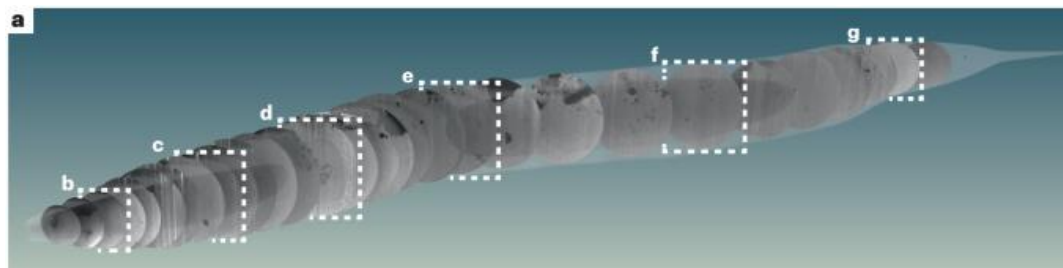
L1 larva of *C. elegans*



SEM



TEM



EPIC-FIB Facility

Access

to Thermo Fisher Hydra Plasma FIB-SEM



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Dr. Yu Wen

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- FIB-SEM experienced users

Questions?

